

# Update on Multi-Megabar Ramp Compression at Z

*Jean-Paul Davis*

*with Marcus D. Knudson, Ray W. Lemke, and others*

*Sandia National Laboratories*

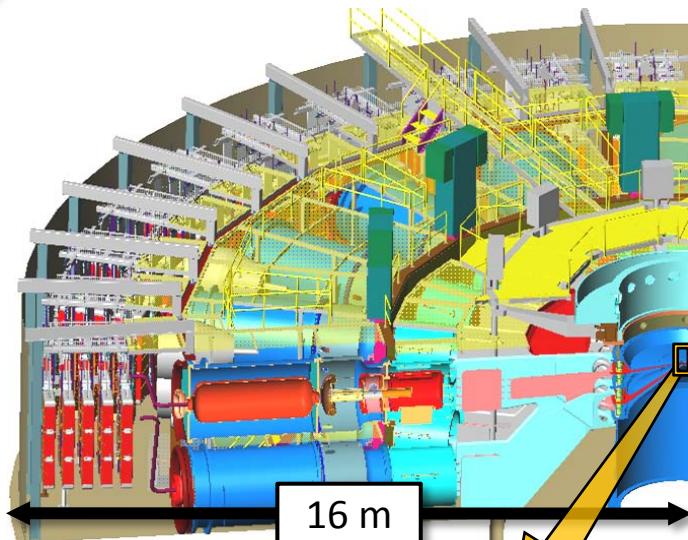
*Albuquerque, NM 87185-1195 USA*



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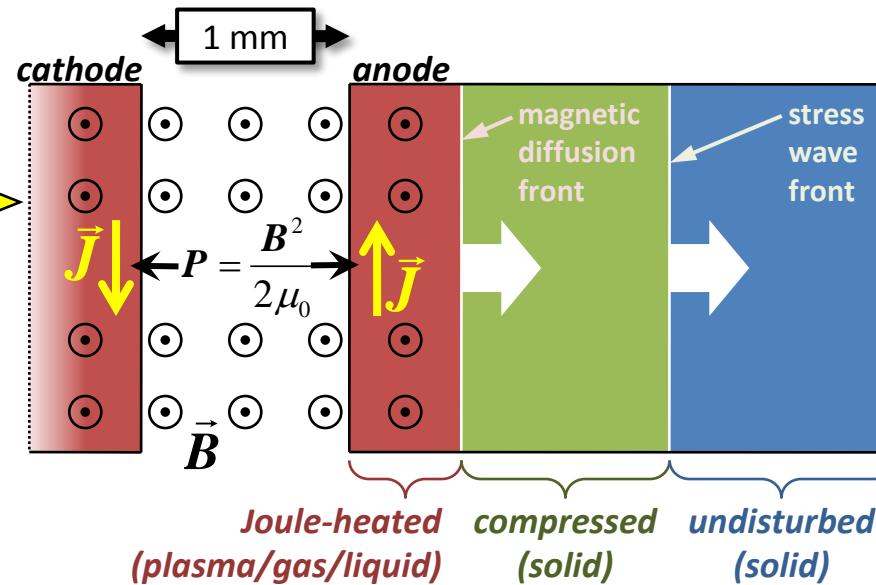
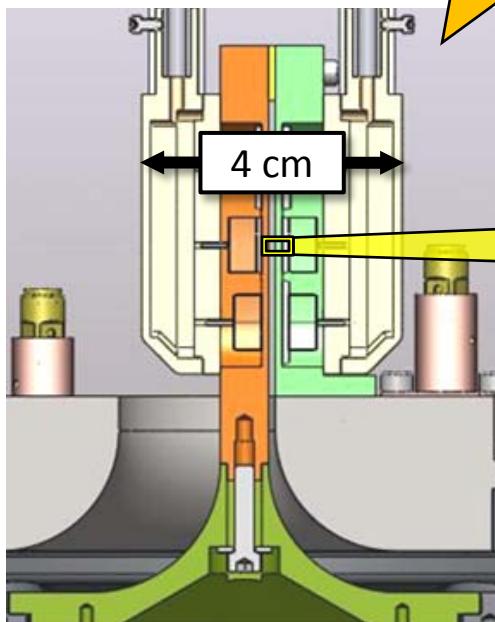


# Refurbished Z machine & stripline load enable accurate ramp-compression experiments to > 300 GPa



16 m

- current pulse of up to 26 MA delivered to parallel flat-plate electrodes shorted at one end
- magnetic ( $\mathbf{J} \times \mathbf{B}$ ) force induces ramped stress wave in electrode material
- stress wave propagates into ambient material, de-coupled from magnetic drive
- controllable pulse shape, rise time 100-700 ns
- identical magnetic loading of sample pairs





## OUTLINE

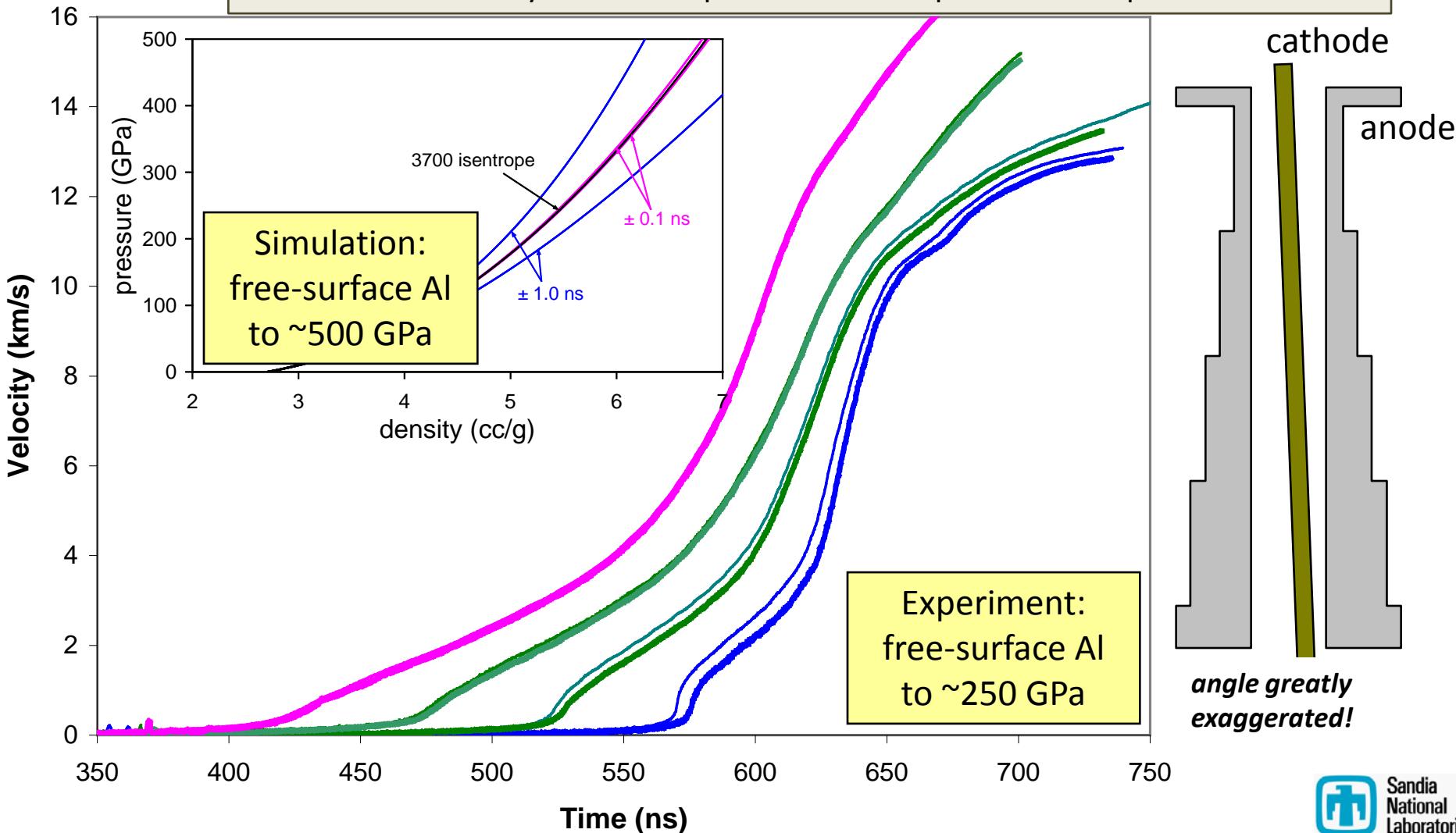
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1. **Stripline load development (6 slides)**
2. **Pulse shaping (2 slides)**
3. **Data analysis (4 slides)**
4. **Preliminary results on tantalum (2 slides)**

# Small misalignments of coaxial anode/cathode geometry can cause significant apparent time shifts

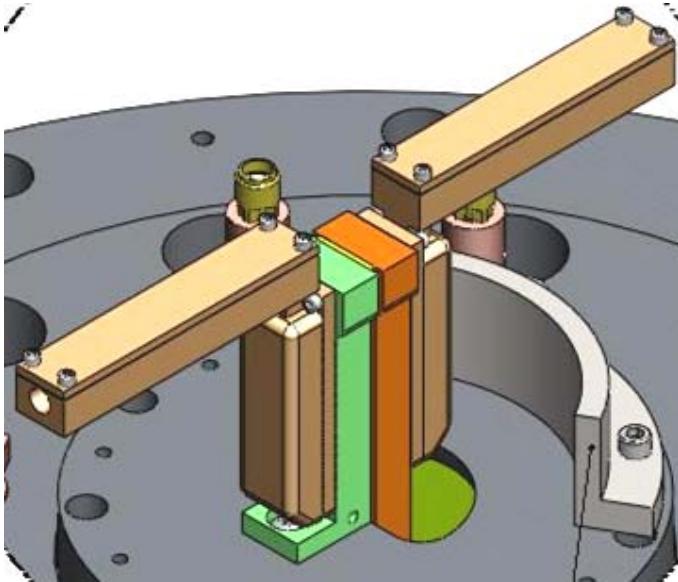
Standard ramp-compression load design on pre-refurbished Z

- samples on separate anodes, two coupled A/K gaps
- 1% uncertainty in stress requires electrodes parallel to  $< 5 \mu\text{m}$  across 25 mm

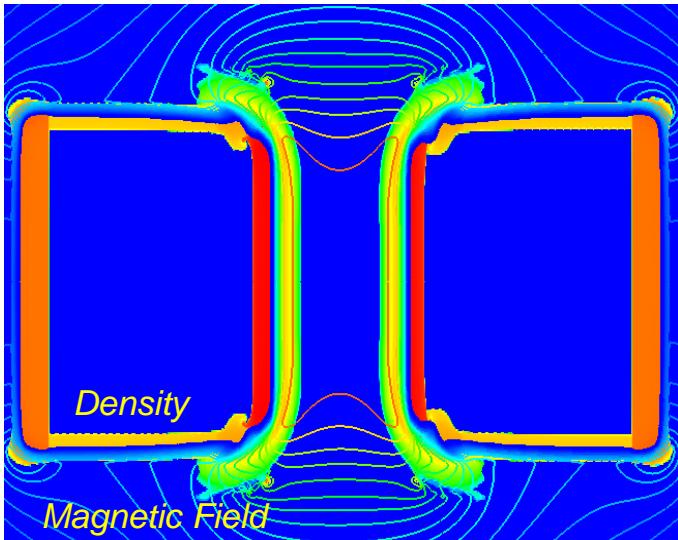




# New stripline geometry offers several advantages

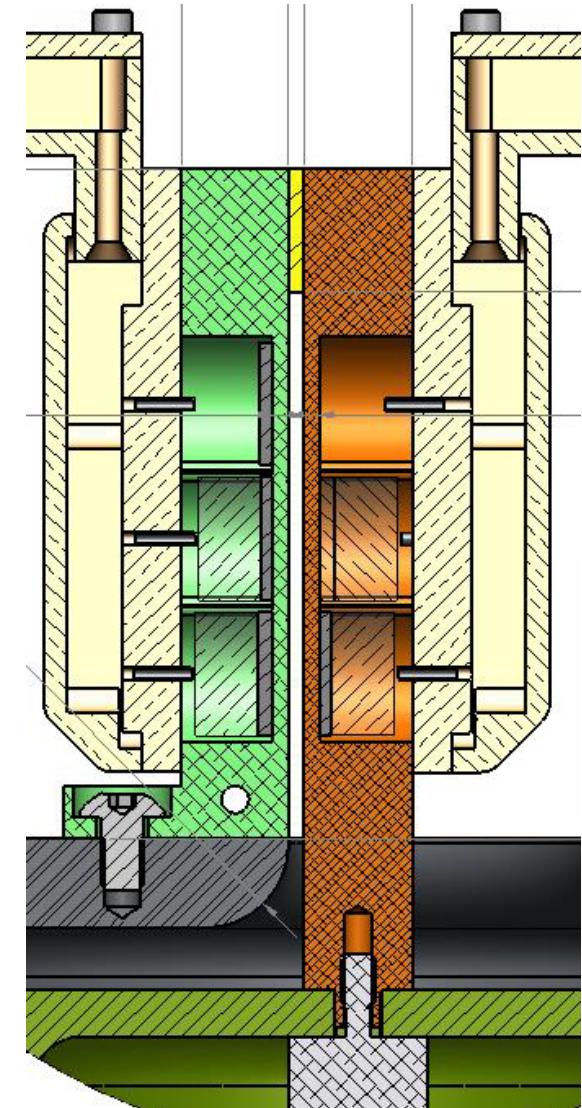


- insensitive to vertical angular misalignment
- single B-field waveform drives two samples
- higher magnetic pressure for given current
- larger lateral extent of uniform 1-D flow

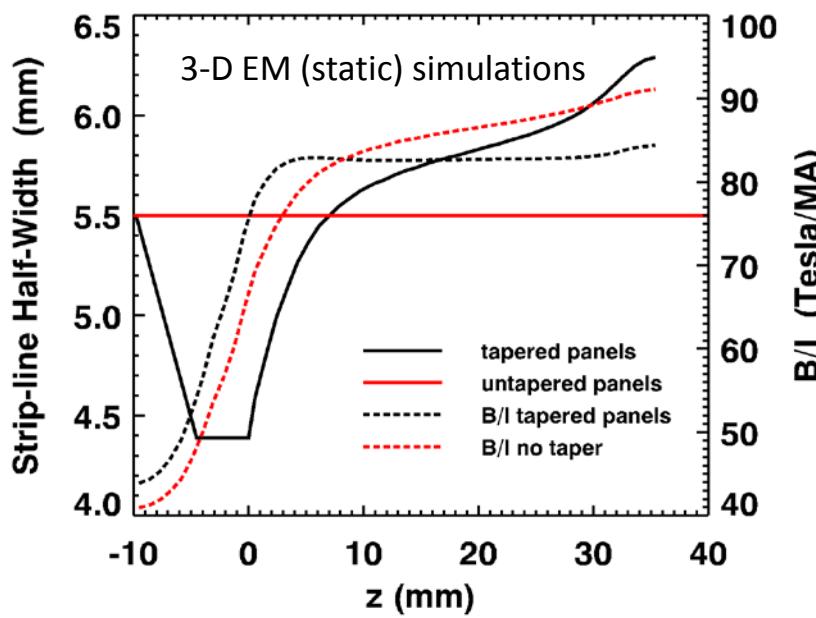
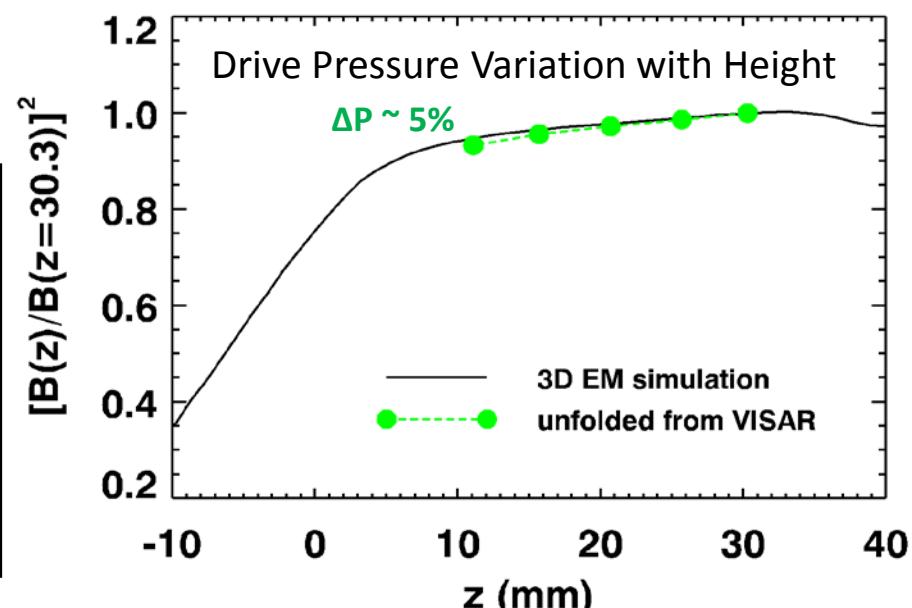
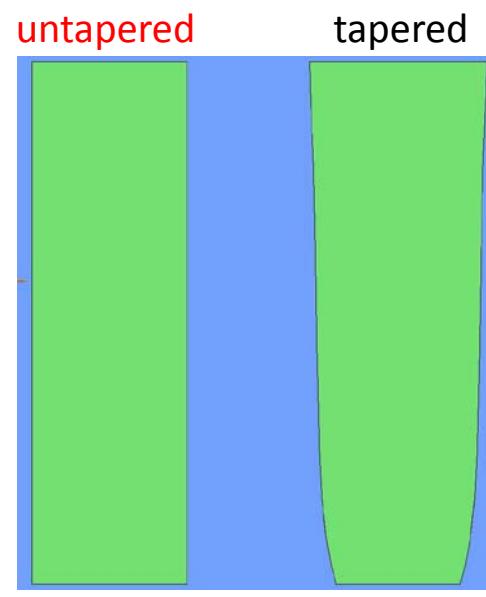
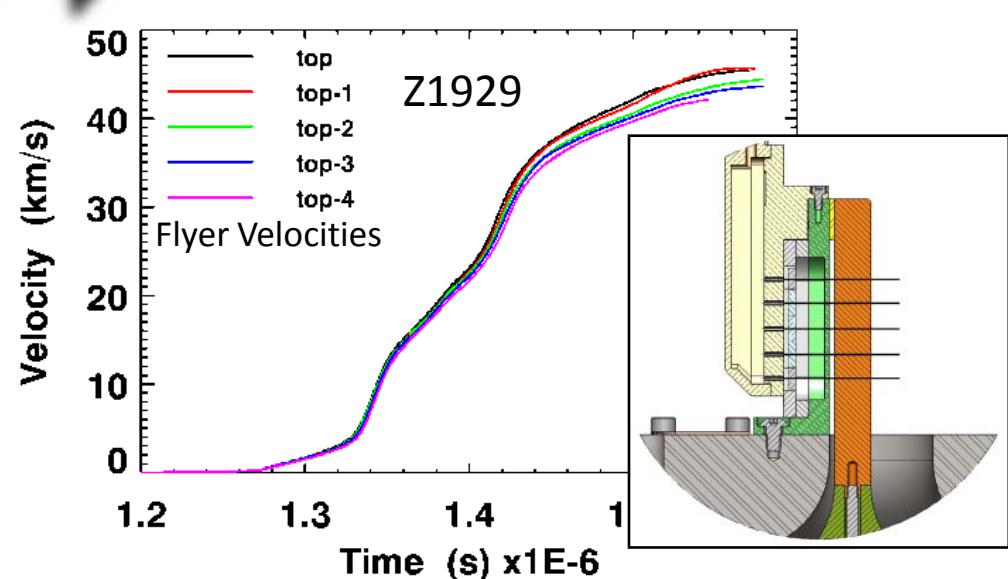


## Unconfined B-field:

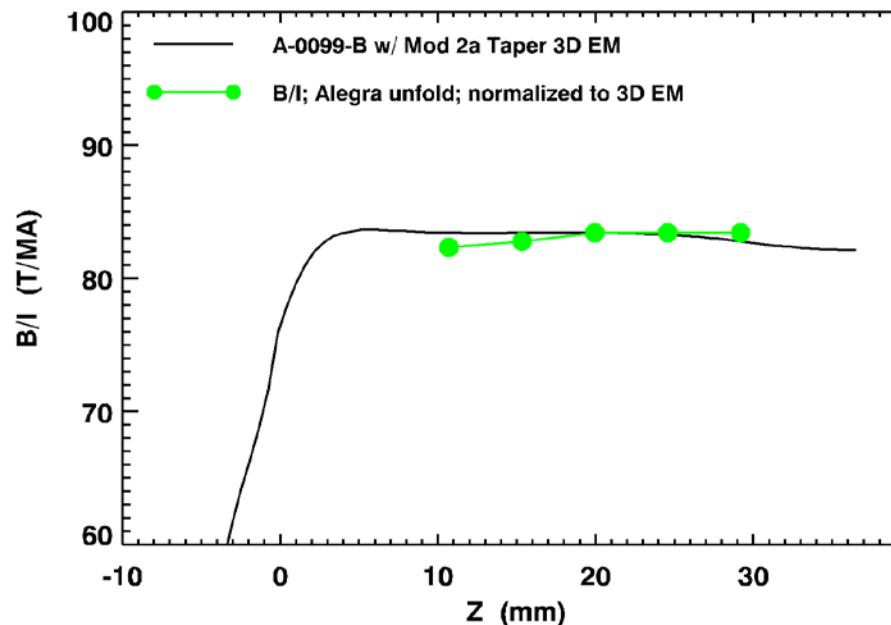
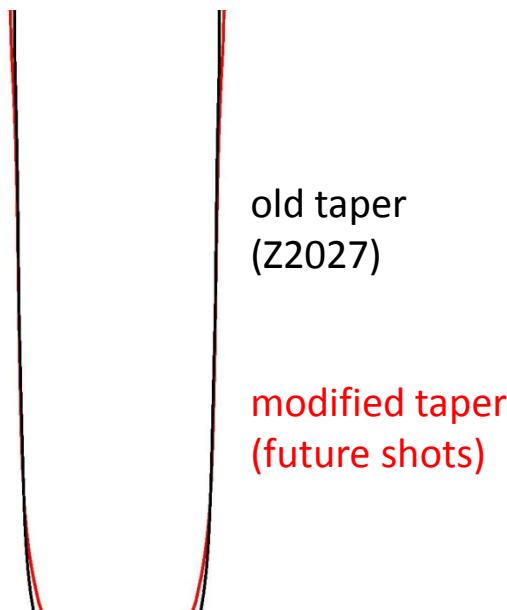
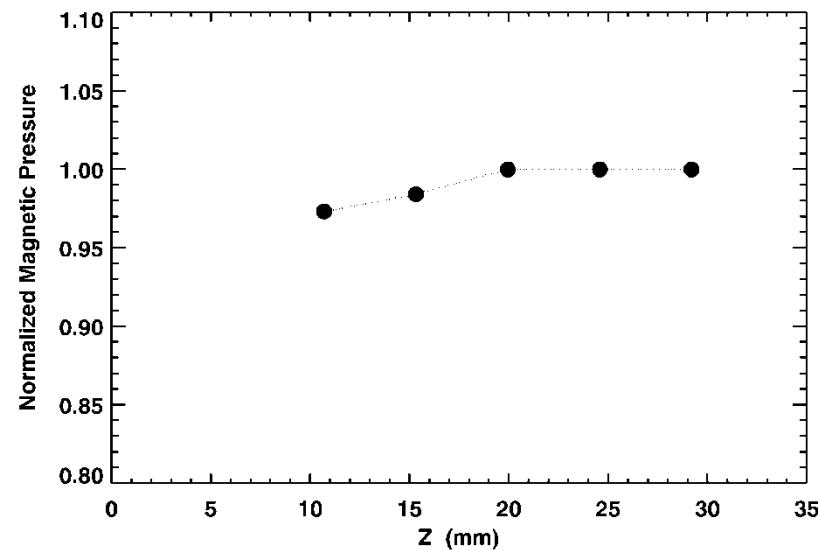
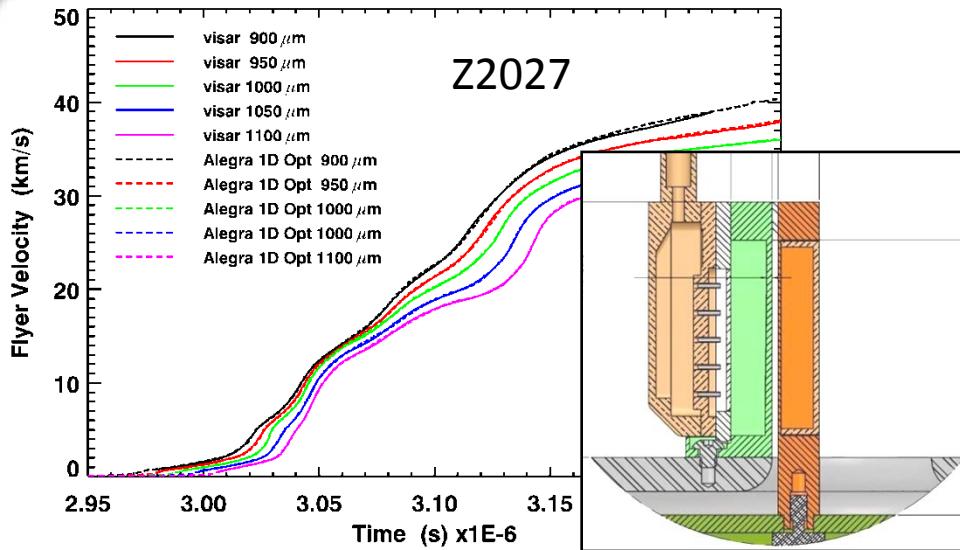
- vertically non-uniform distribution of current inside/outside the gap
- shielding of diagnostics and samples



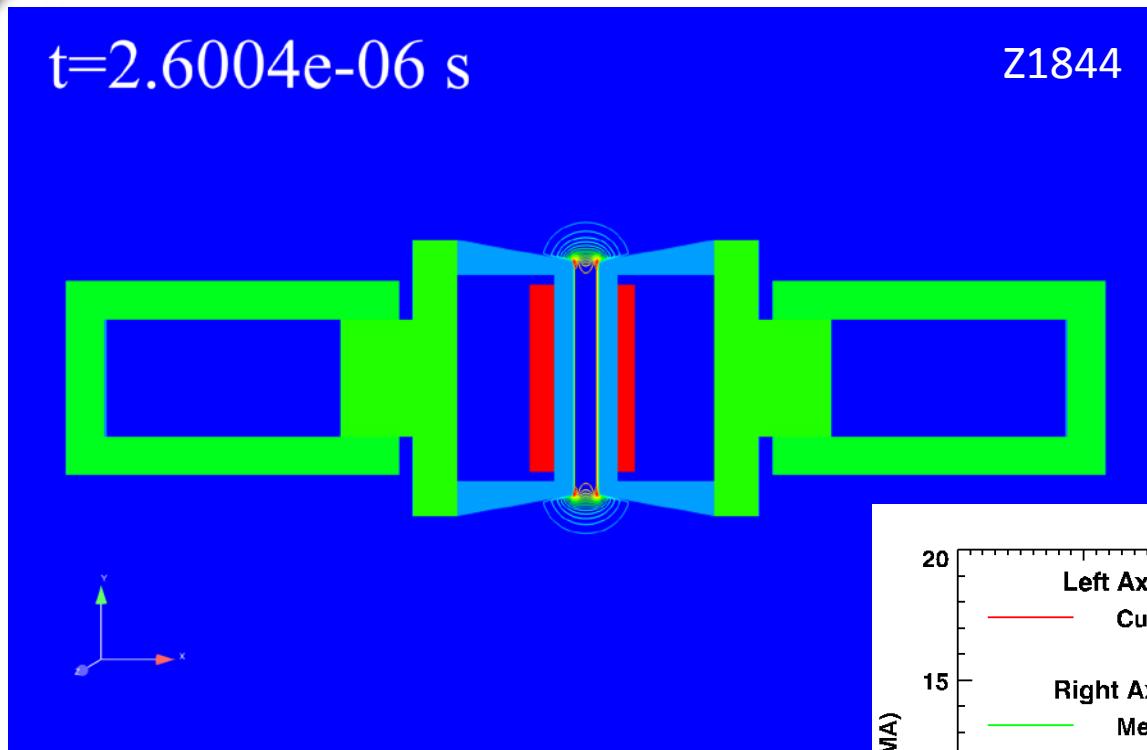
# Measurement of vertical non-uniformity of B-field shows need for functional tapering of stripline width



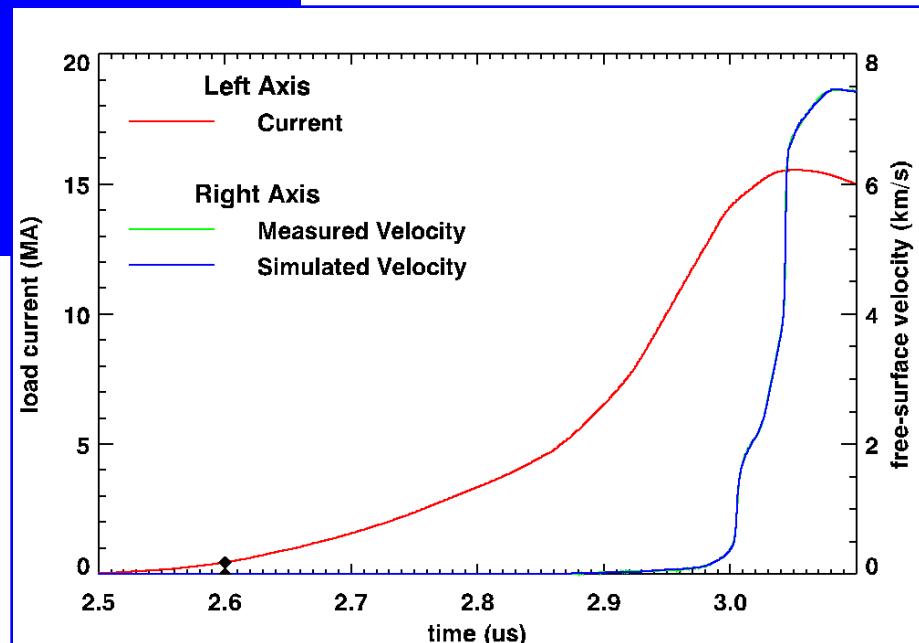
# Semi-empirical functional tapering of stripline width should eliminate vertical non-uniformity of B-field



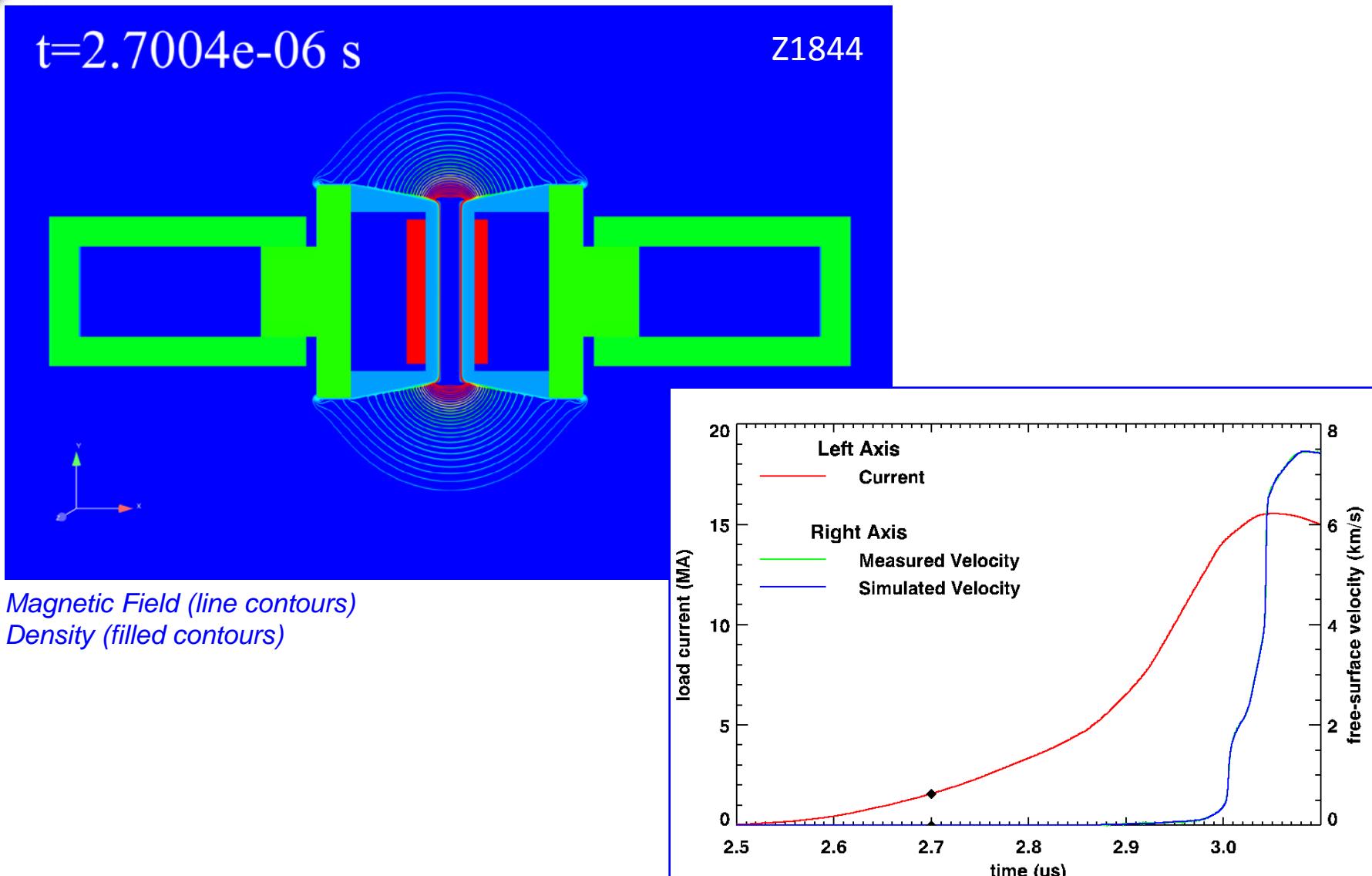
# Simulations predict highly uniform B-field in the lateral and normal directions over most of the gap



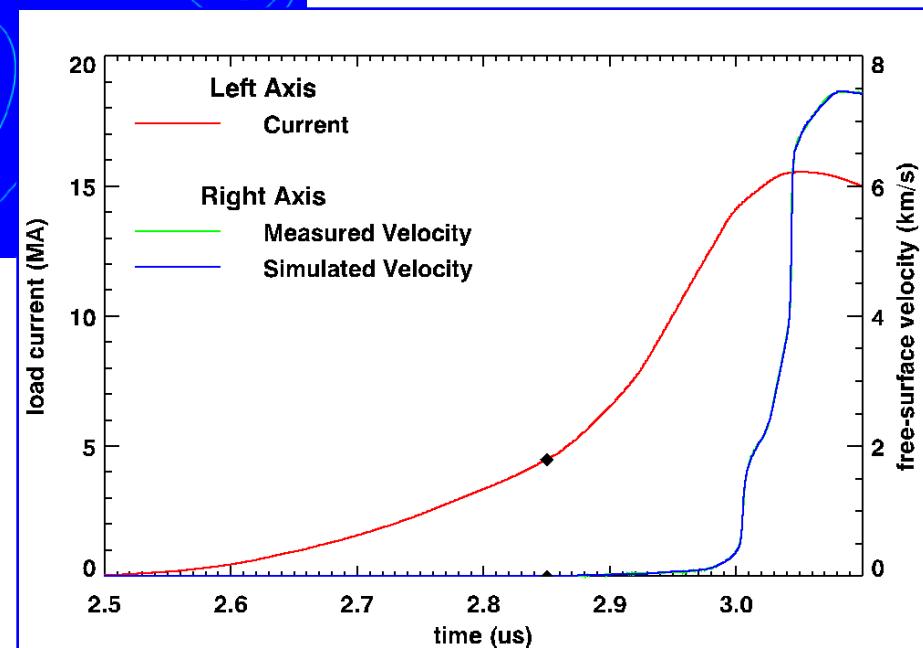
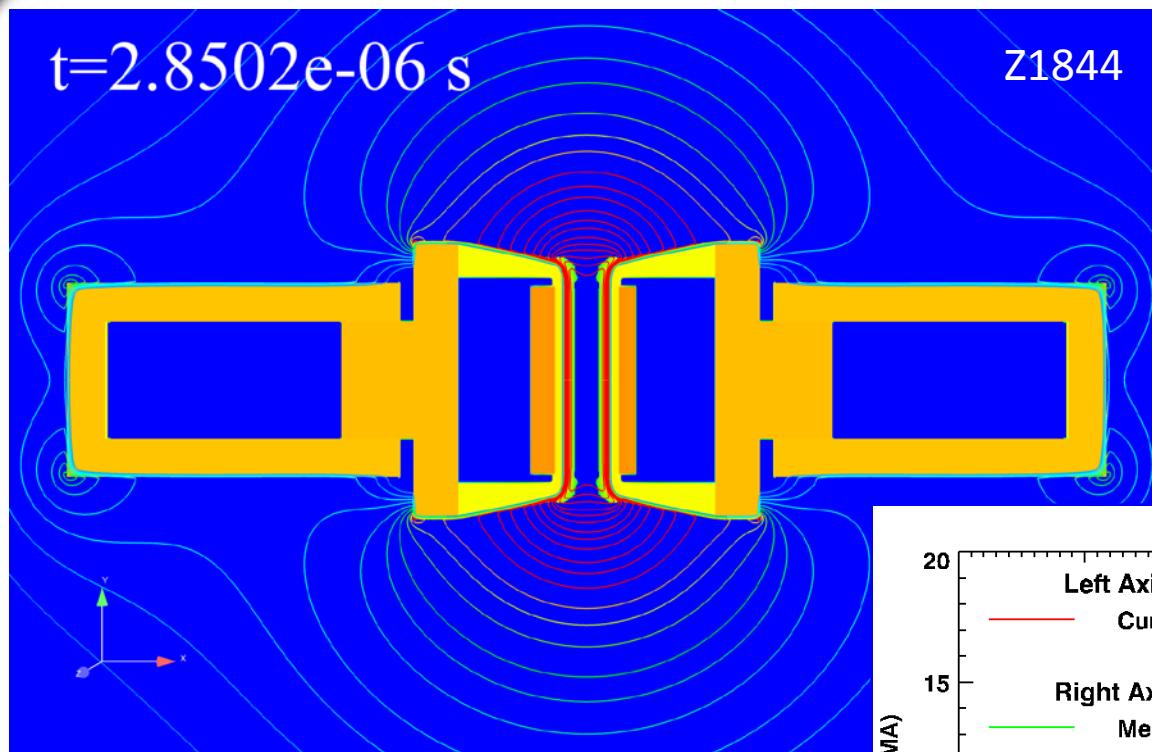
**2-D Alegra-MHD:**  
Resistive MHD  
QMD/LMD conductivity  
Sesame EOS  
Circuit model



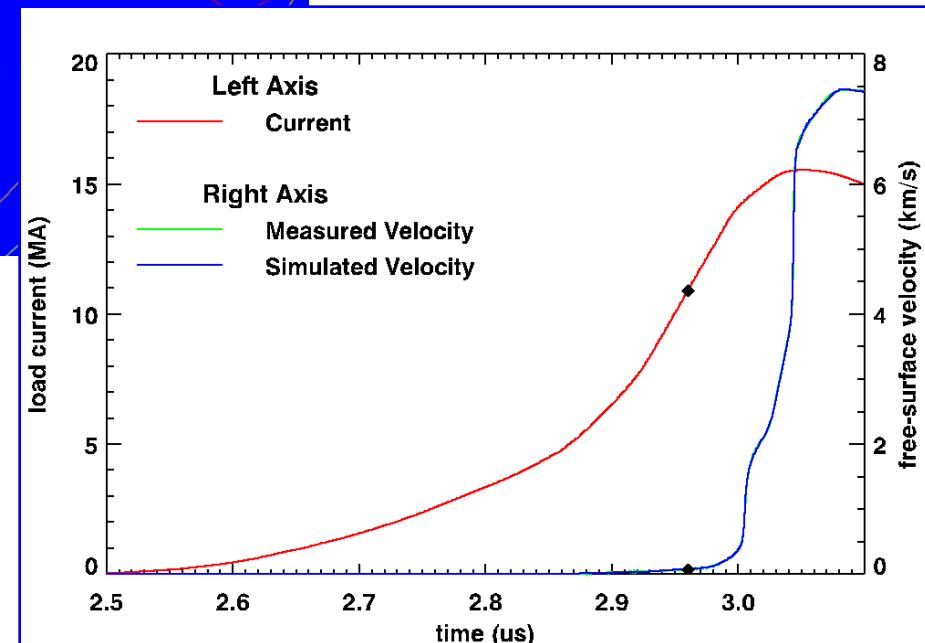
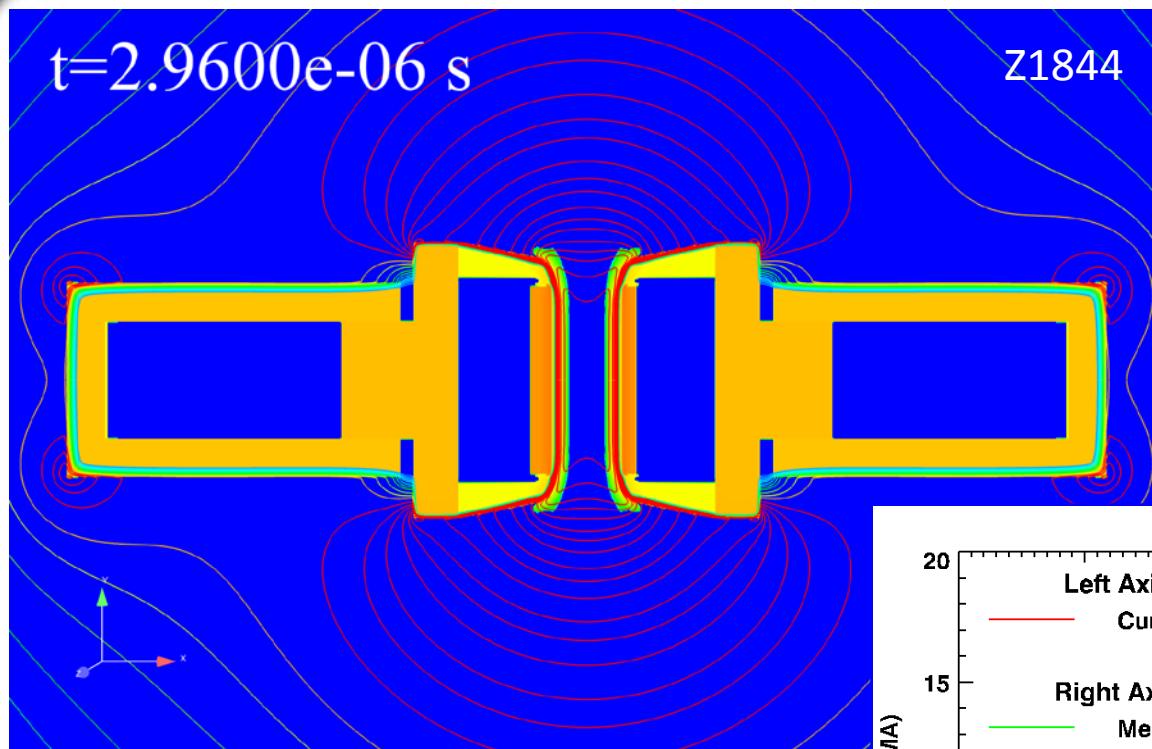
# Simulations predict highly uniform B-field in the lateral and normal directions over most of the gap



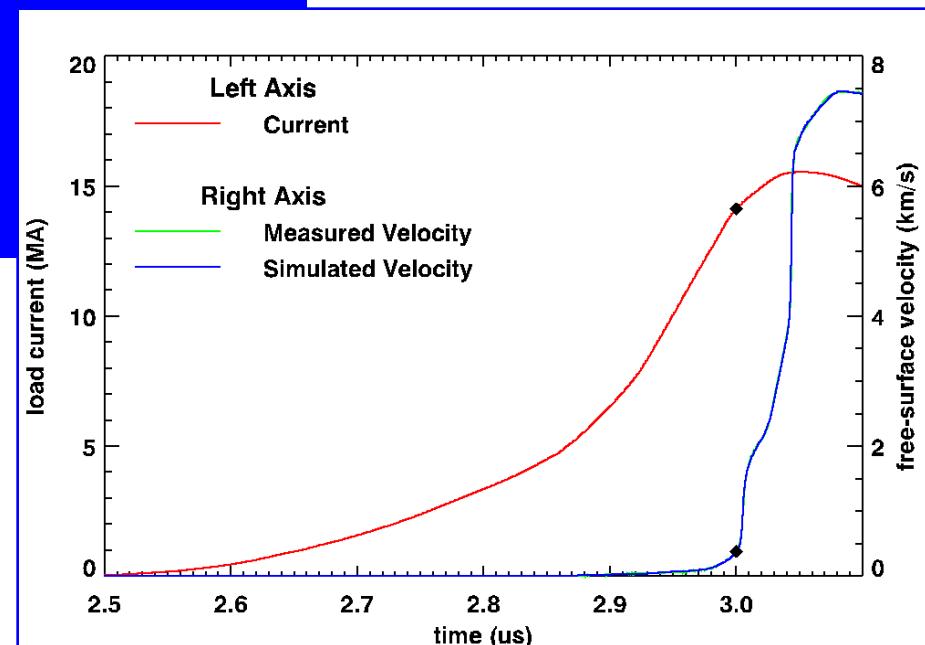
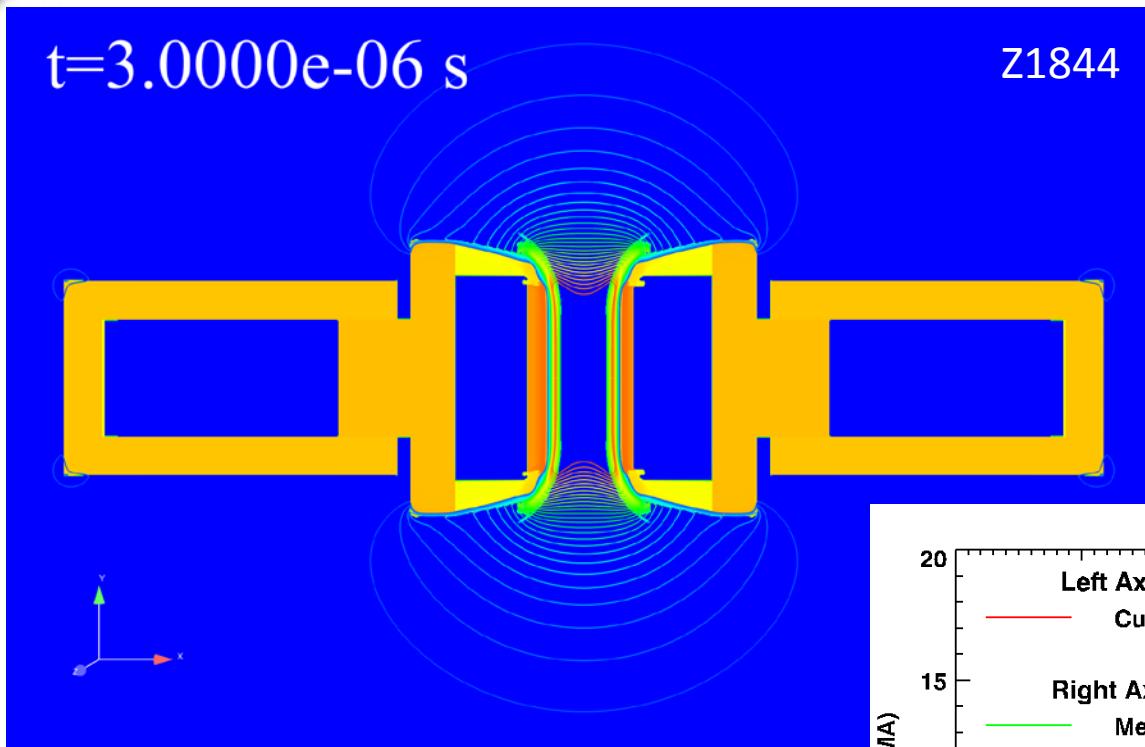
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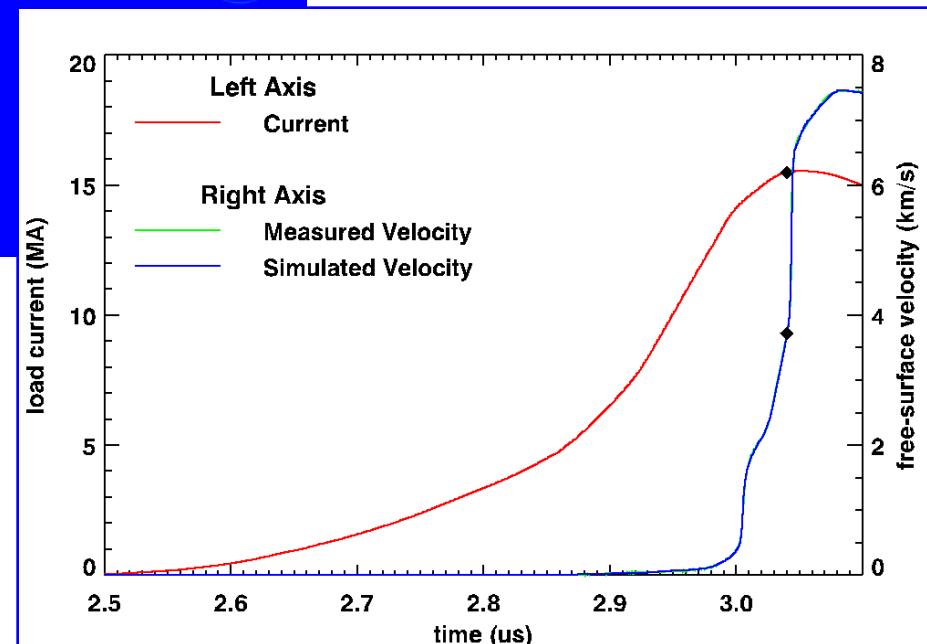
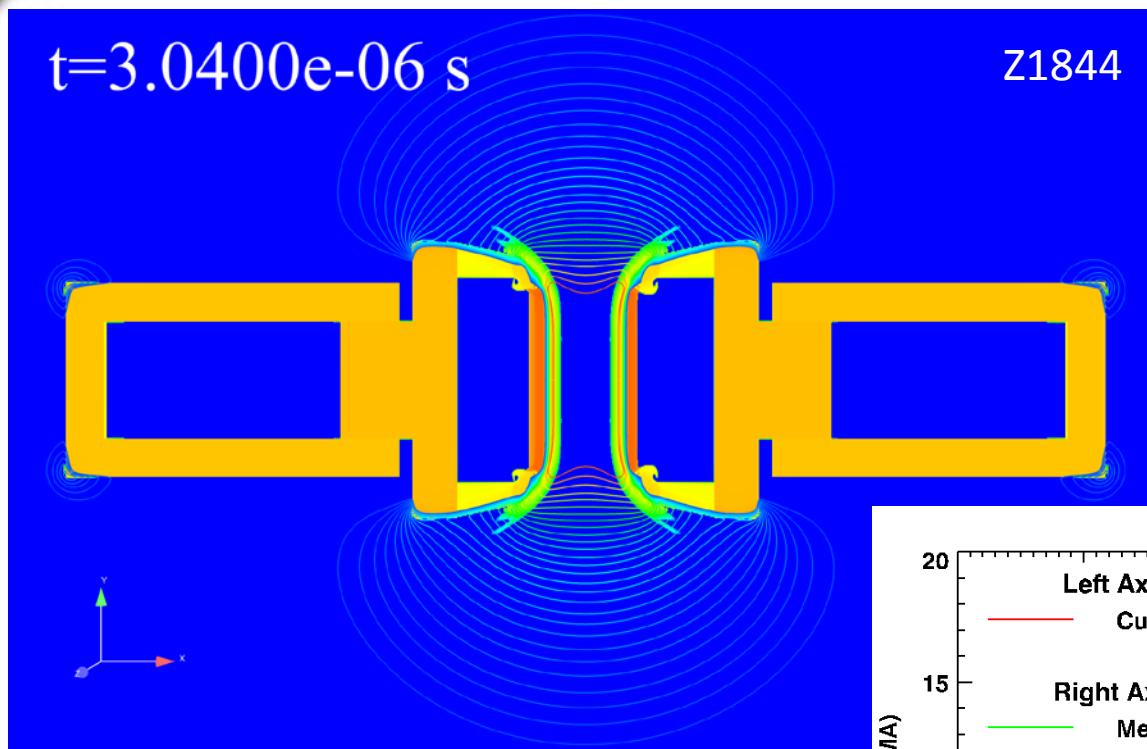
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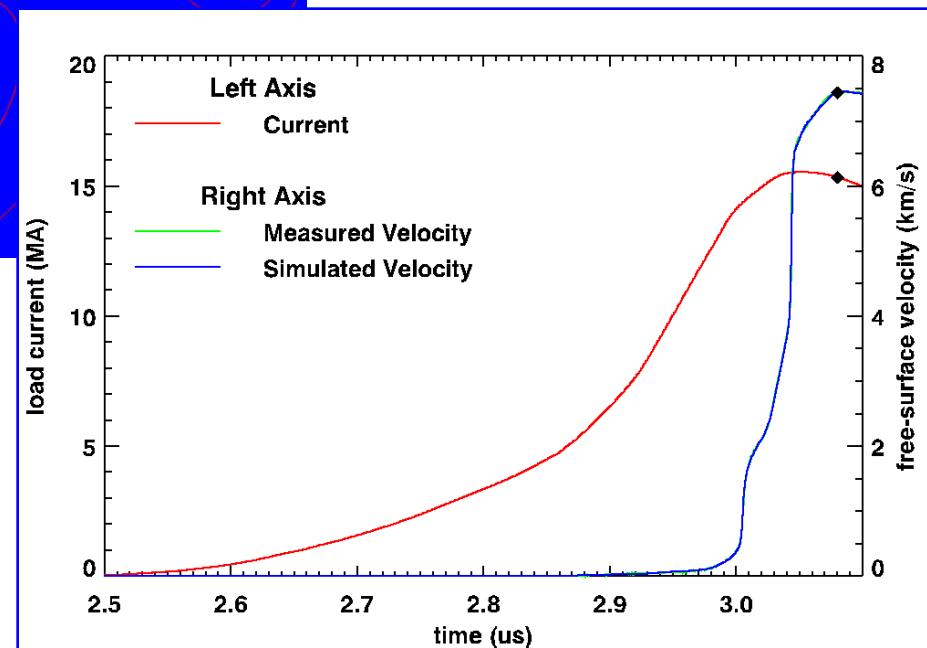
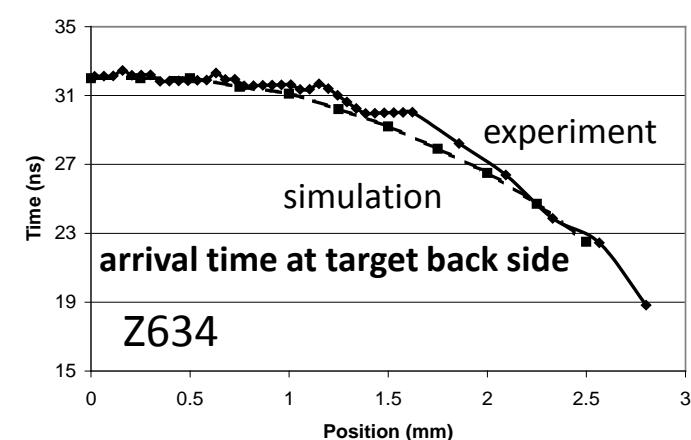
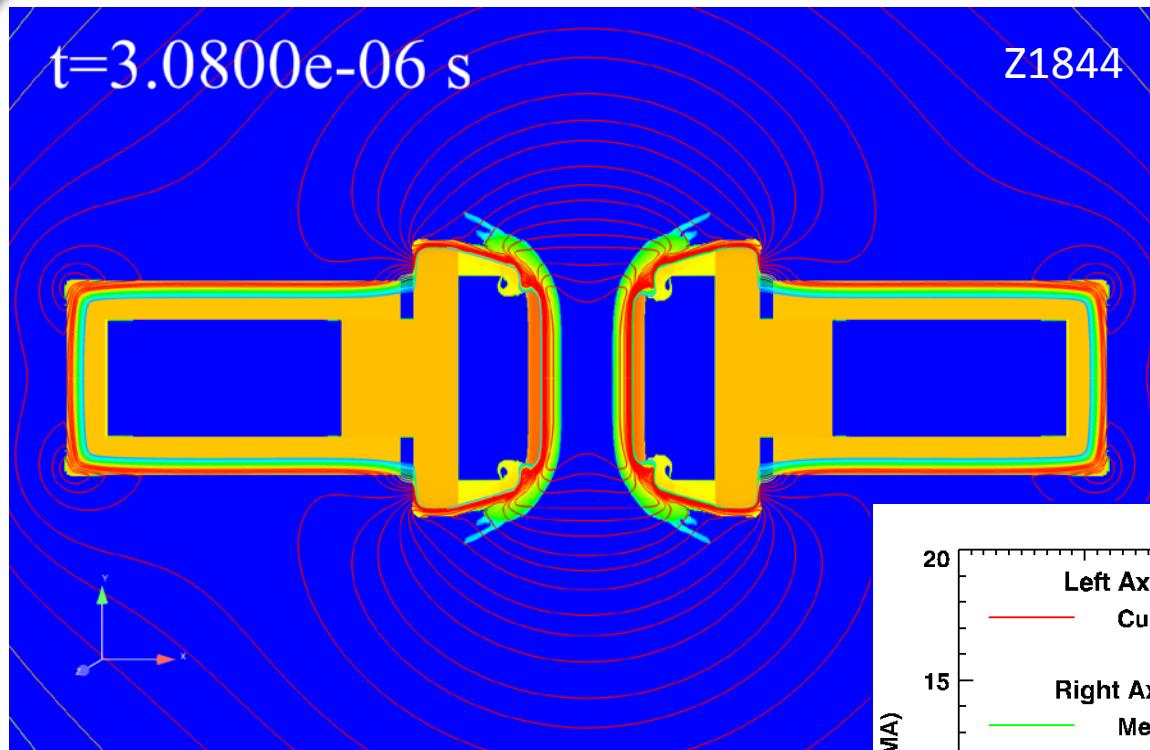
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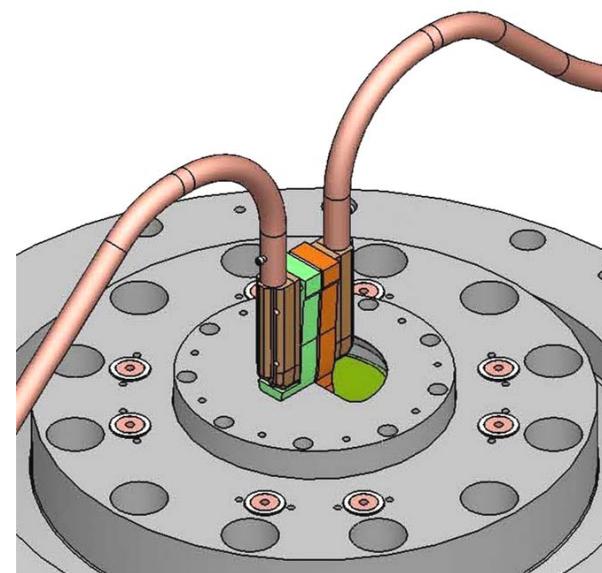
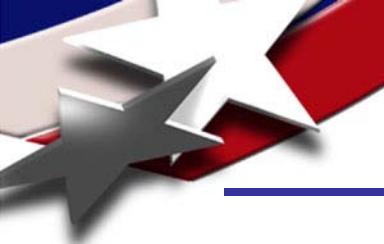
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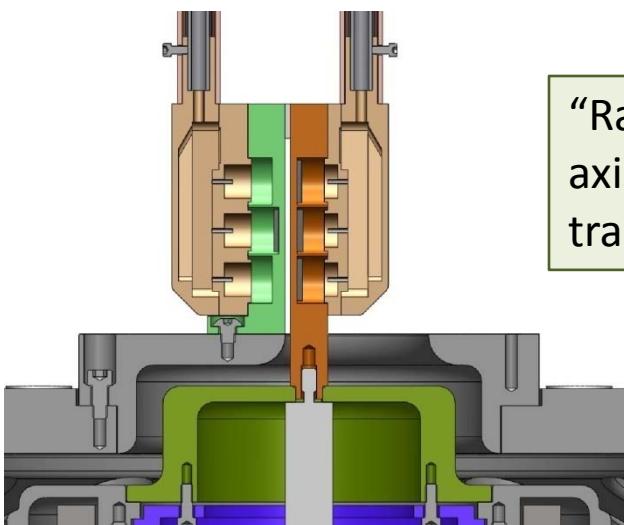
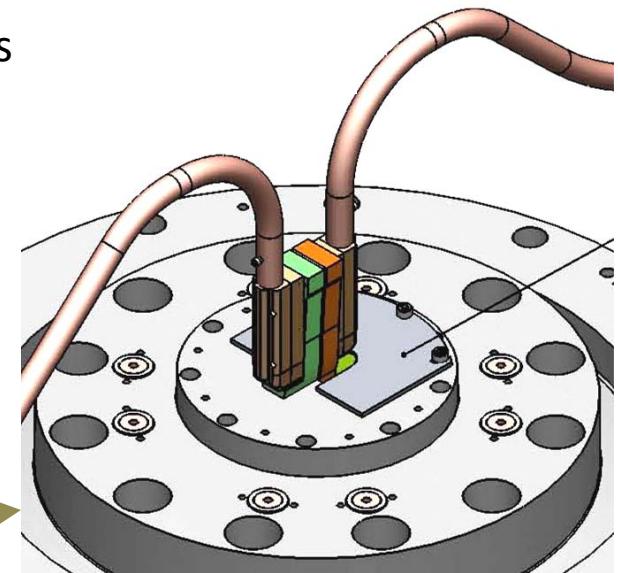


# VISAR fiber darkening issues have been addressed

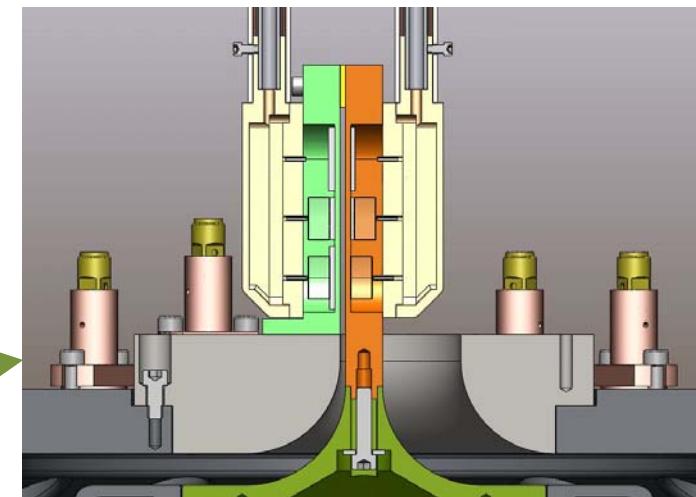


X-rays generated at corners  
inside inner-MITL feed?

“D-hole” anode opening  
decreased to 4-mm  
minimum A-K distance

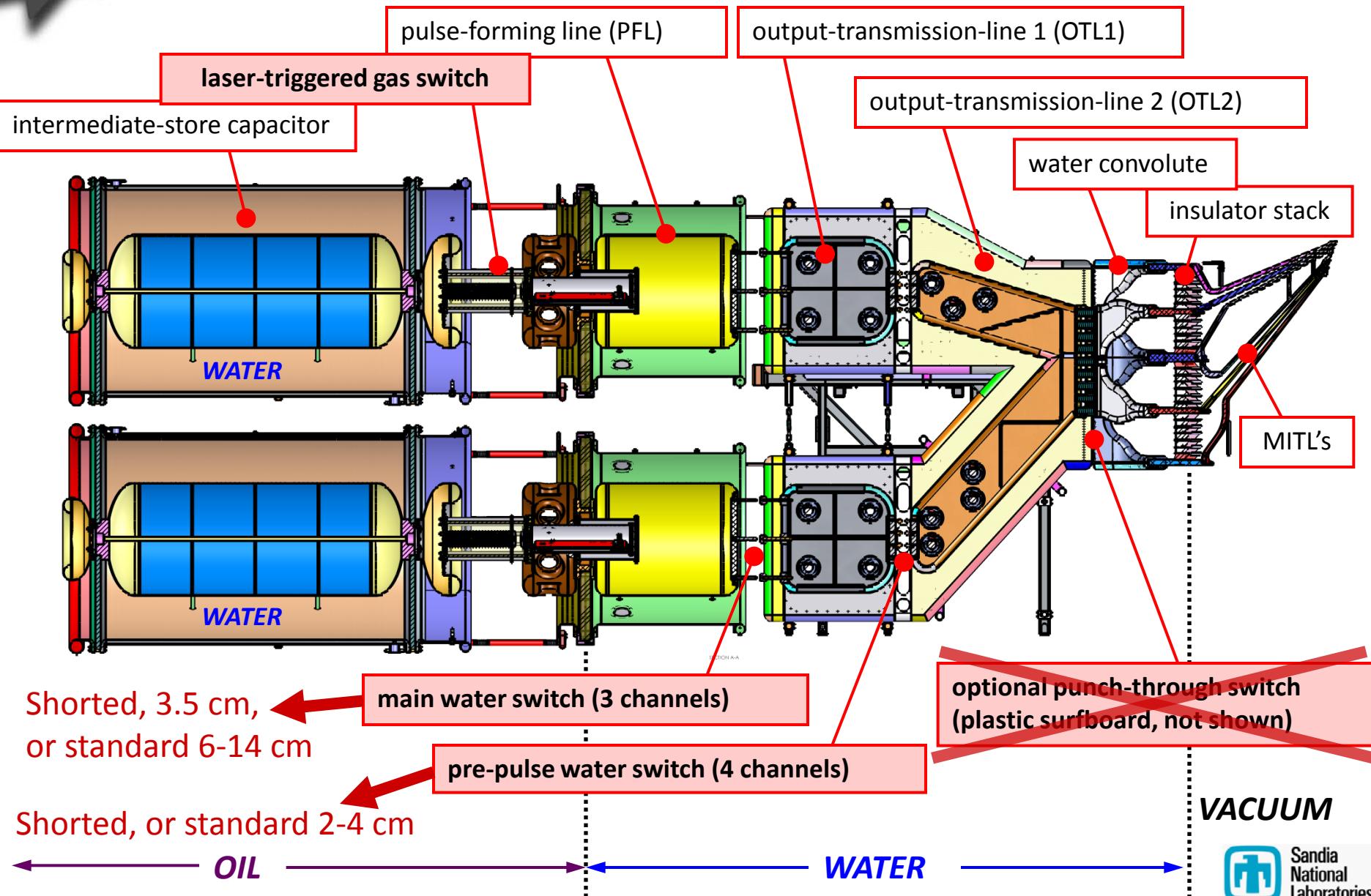


“Radial” feed for  
axisymmetric-to-stripline  
transition



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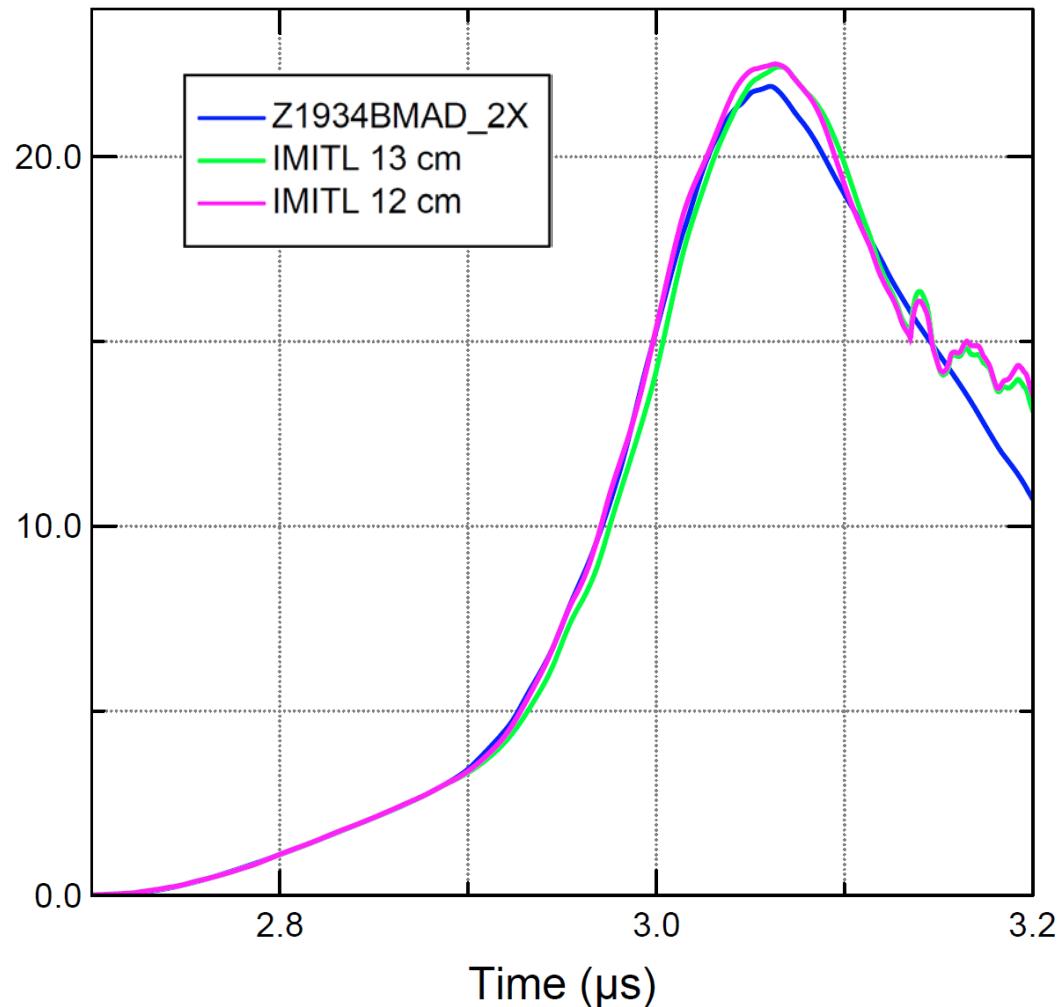
# Shaped pulses are obtained by staggering gas-switch times and modifying water switches



# Recent improvements to the Bertha circuit model of Z have increased accuracy of predictions

Recovers effect of 1-cm change in main water-switch gaps of 30 short-pulse lines!

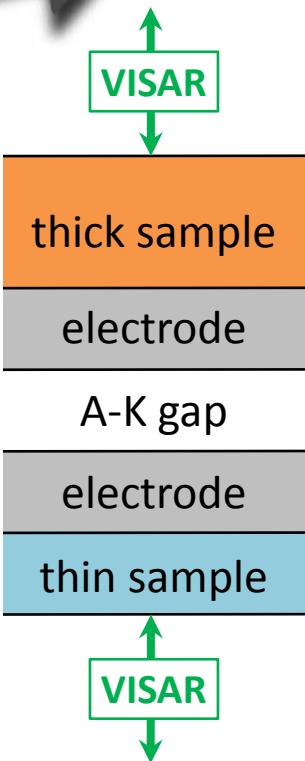
85-kV standard = 13cm gap  
Z1934 at 12cm instead  
(standard for 80-KV on Z1933)



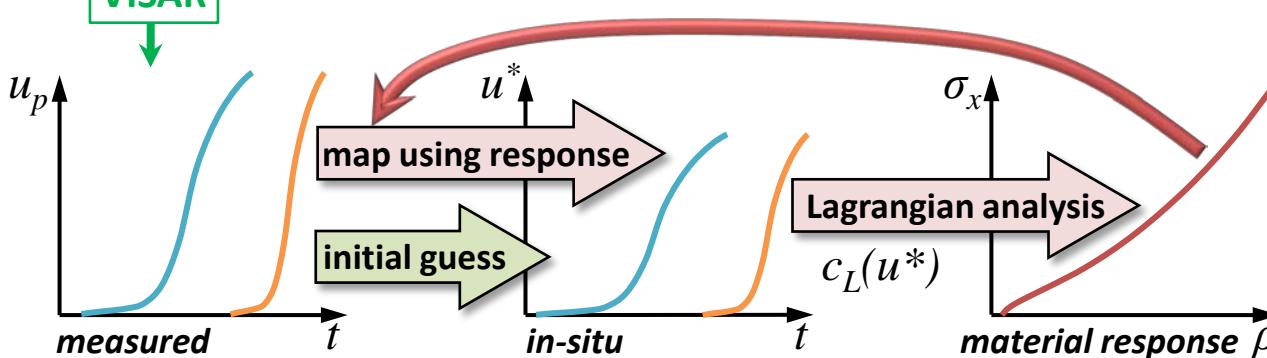
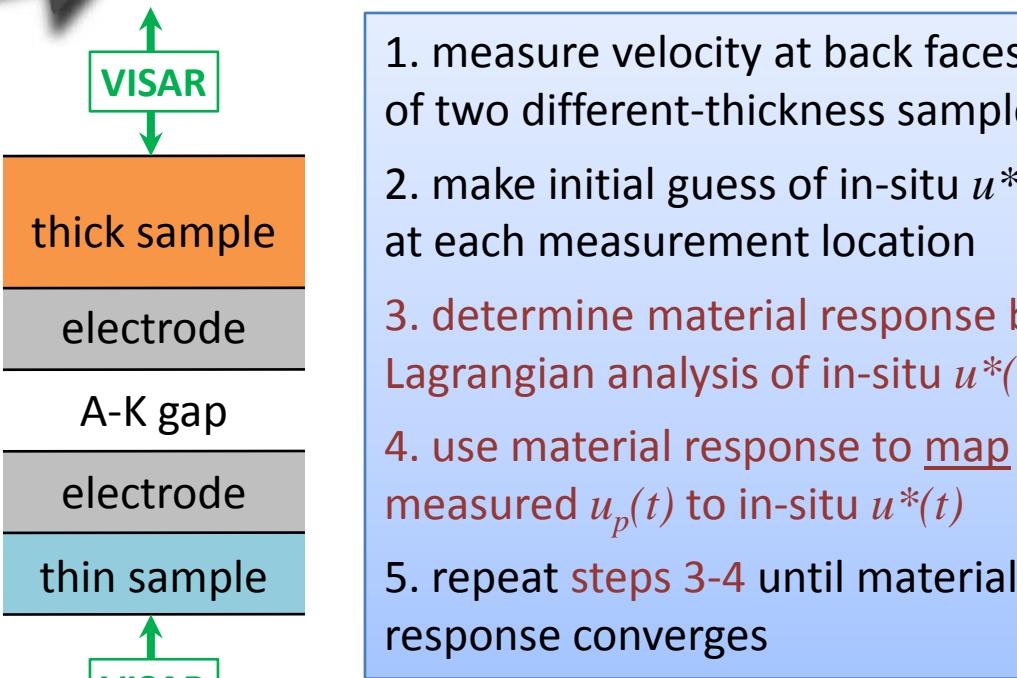
- working with L-3 Communications on final version of model
- calibrate pulse-forming section against flat-MITL shots
- will include 2-D transmission-line sections (OTL2, stack and outer MITLs)



# Inverse Lagrangian analysis of velocity from two samples gives quasi-isentropic stress-density response

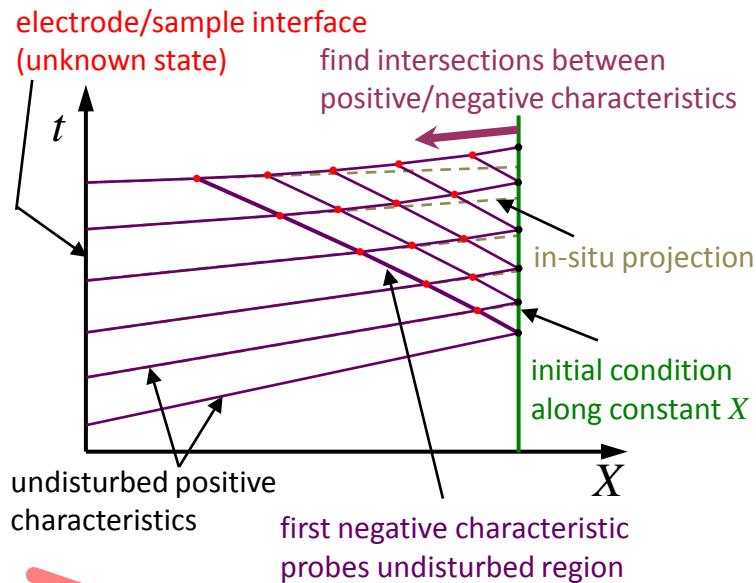
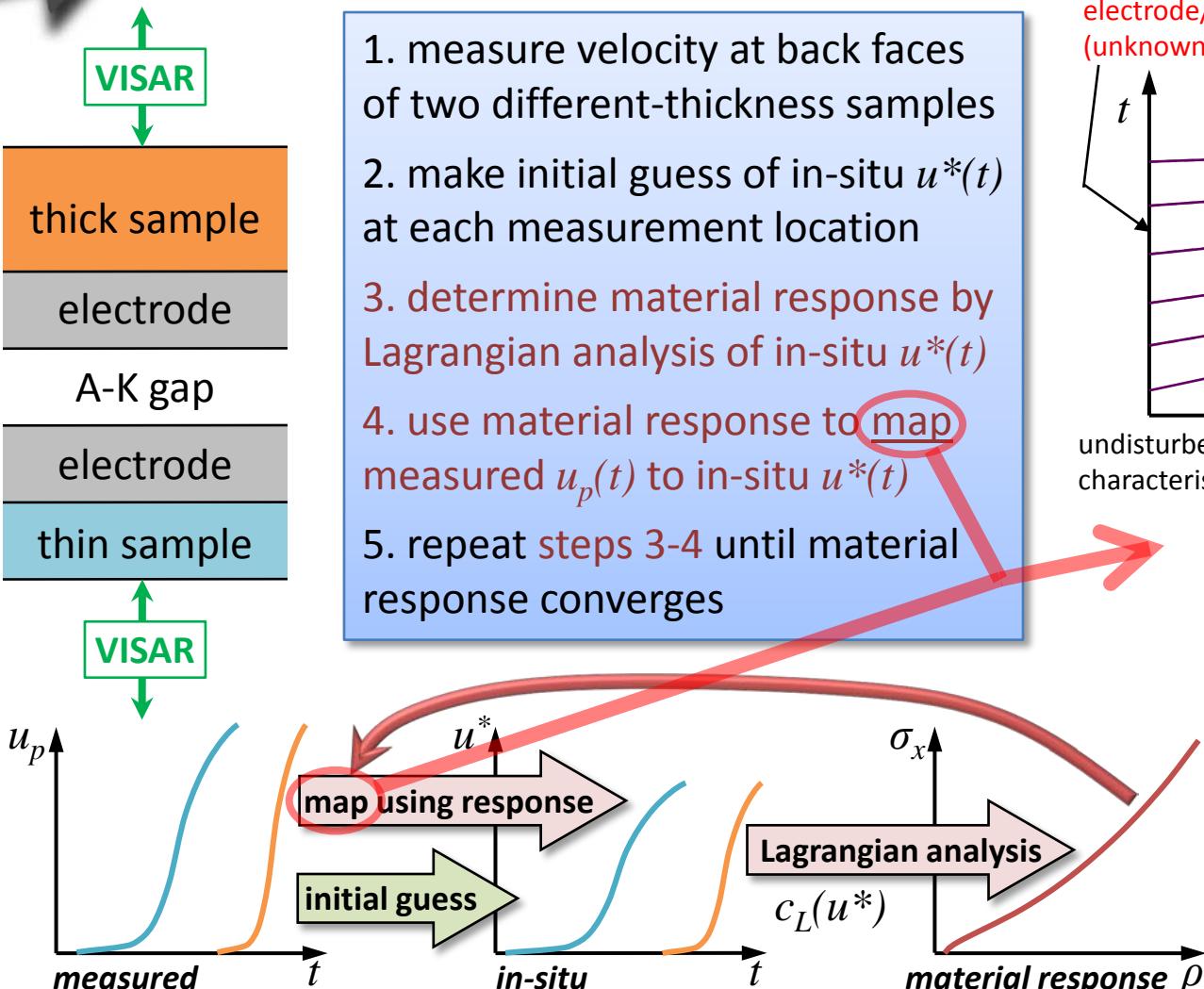


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- assumes isentropic, simple-wave behavior
- valid ONLY while electrode/sample interface states identical

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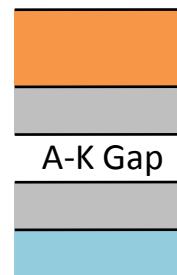
- use Riemann invariants to solve intersections between
  1. negative characteristics projected forward in time
  2. positive characteristics projected backward in time
- project points on 1<sup>st</sup> negative characteristic forward to measurement position

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- valid ONLY while electrode/sample interface states identical



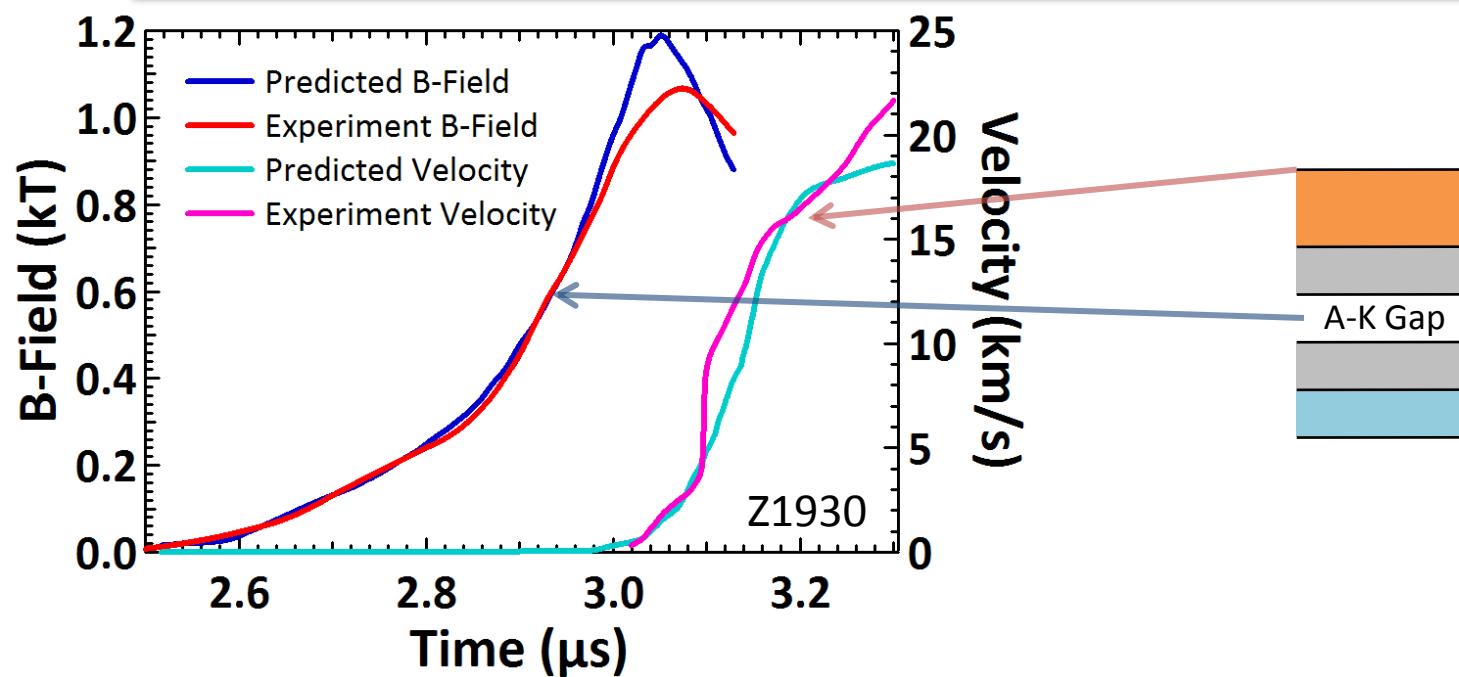
## Two-sample approach is limited in accuracy and maximum stress by pulse shape and reverberation

- uncertainty in  $c_L = \Delta X / \Delta t$  depends on relative uncertainty in thickness difference
  - must maximize difference in thickness between samples



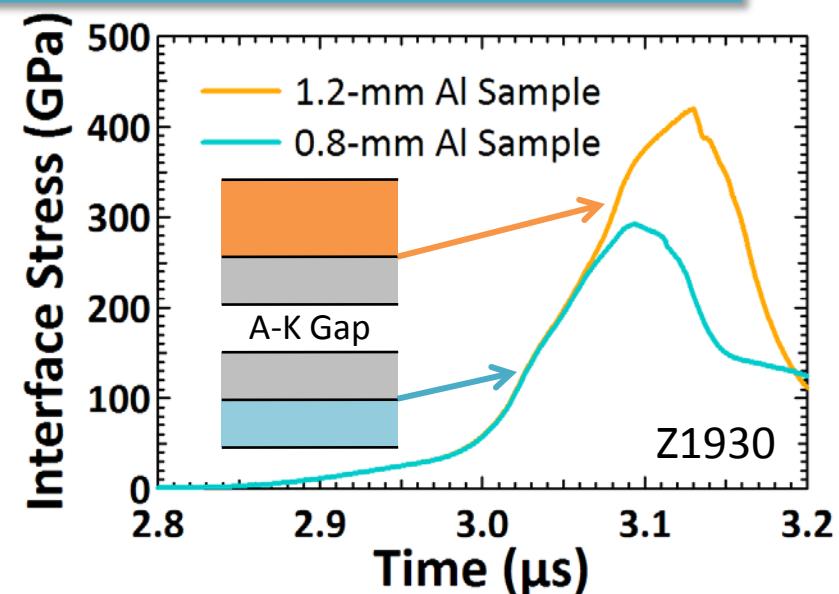
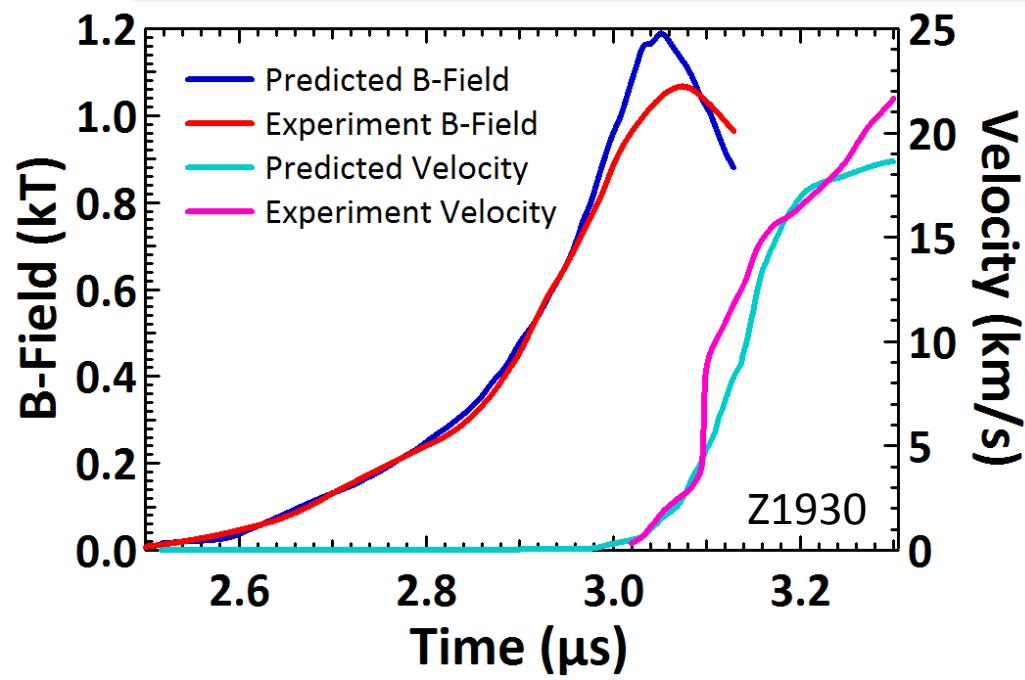
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  - imprecision in pulse shaping makes ideal shock-up distance difficult to attain



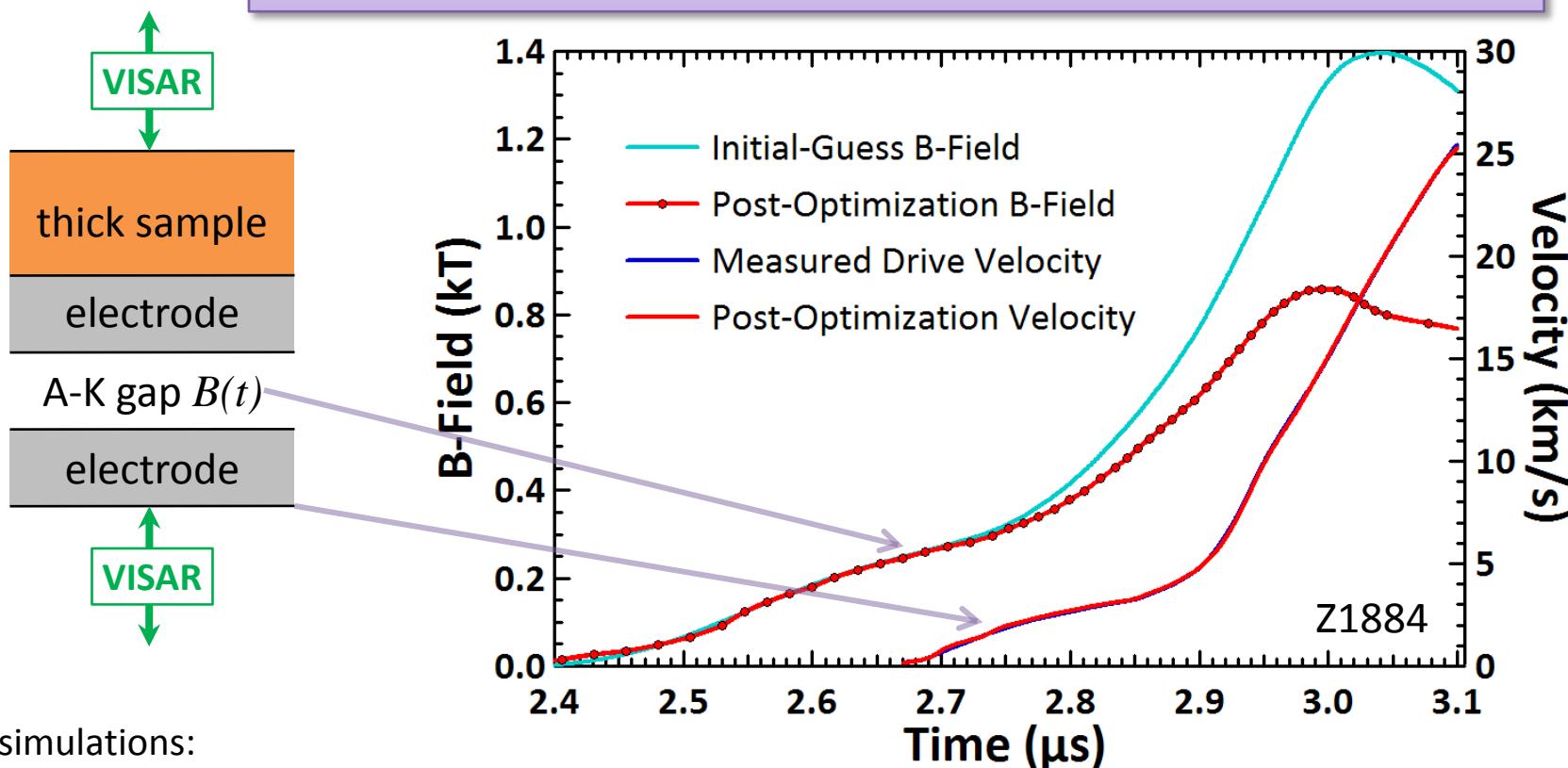
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- arrival of back-surface reflection at sample's front surface (reverberation) limits **minimum thickness** to achieve desired stress state
- increasing rise time to delay shock formation in thick sample reduces peak stress at front surface of thin sample



# Optimization technique determines magnetic-field history in A-K gap from electrode “drive” measurement

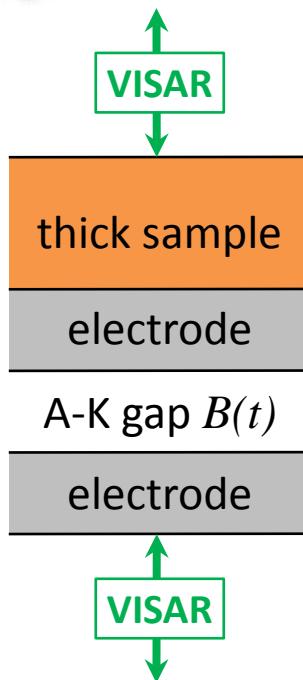
- Dakota optimization framework drives Alegra 1-D MHD simulations
- $B(t)$  represented by constrained cubic spline (25-50 points) with time shift and stretch factors
- objective function is metric of isometry between simulated and experimental velocity history at electrode back surface



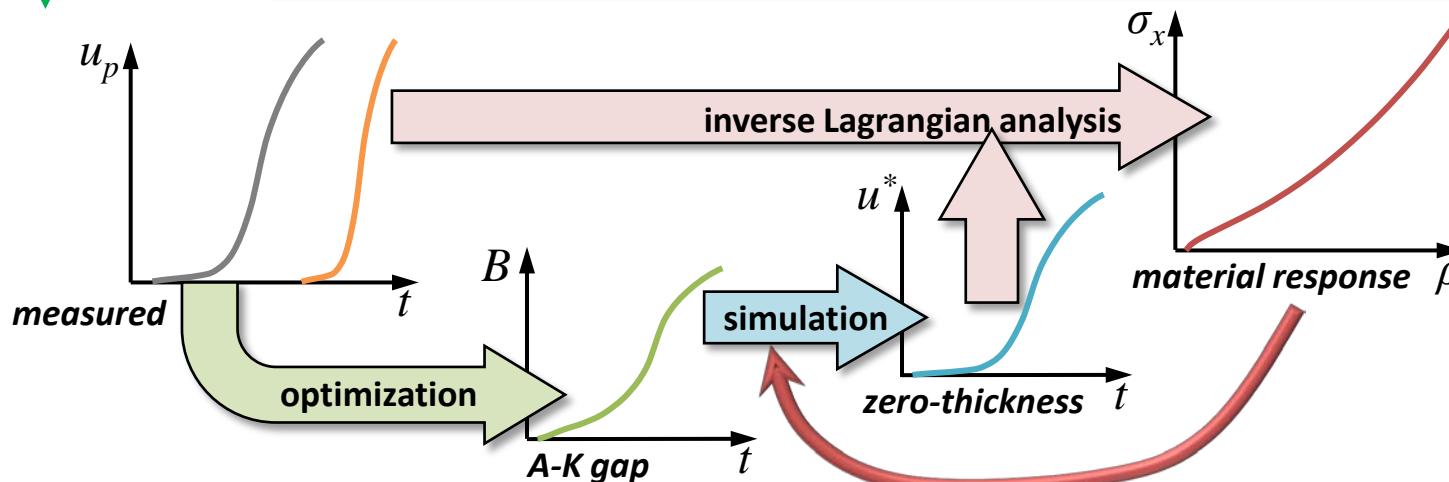
MHD simulations:

- high confidence in aluminum EOS and conductivity models
- high spatial resolution (2.5-μm cells)

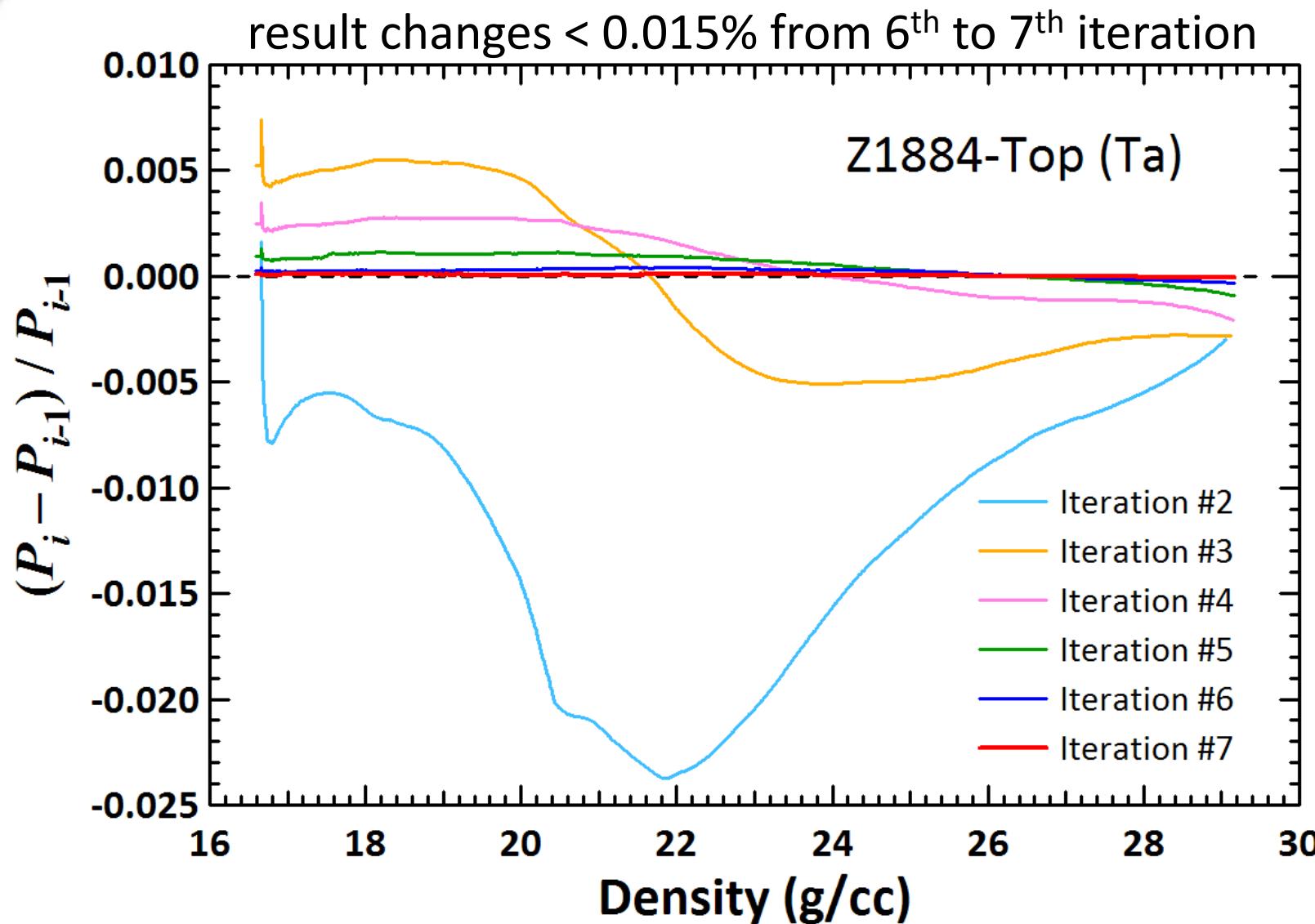
# Single sample yields quasi-isentrope by iterating inverse Lagrangian analysis with simulated “zero-thickness” velocity



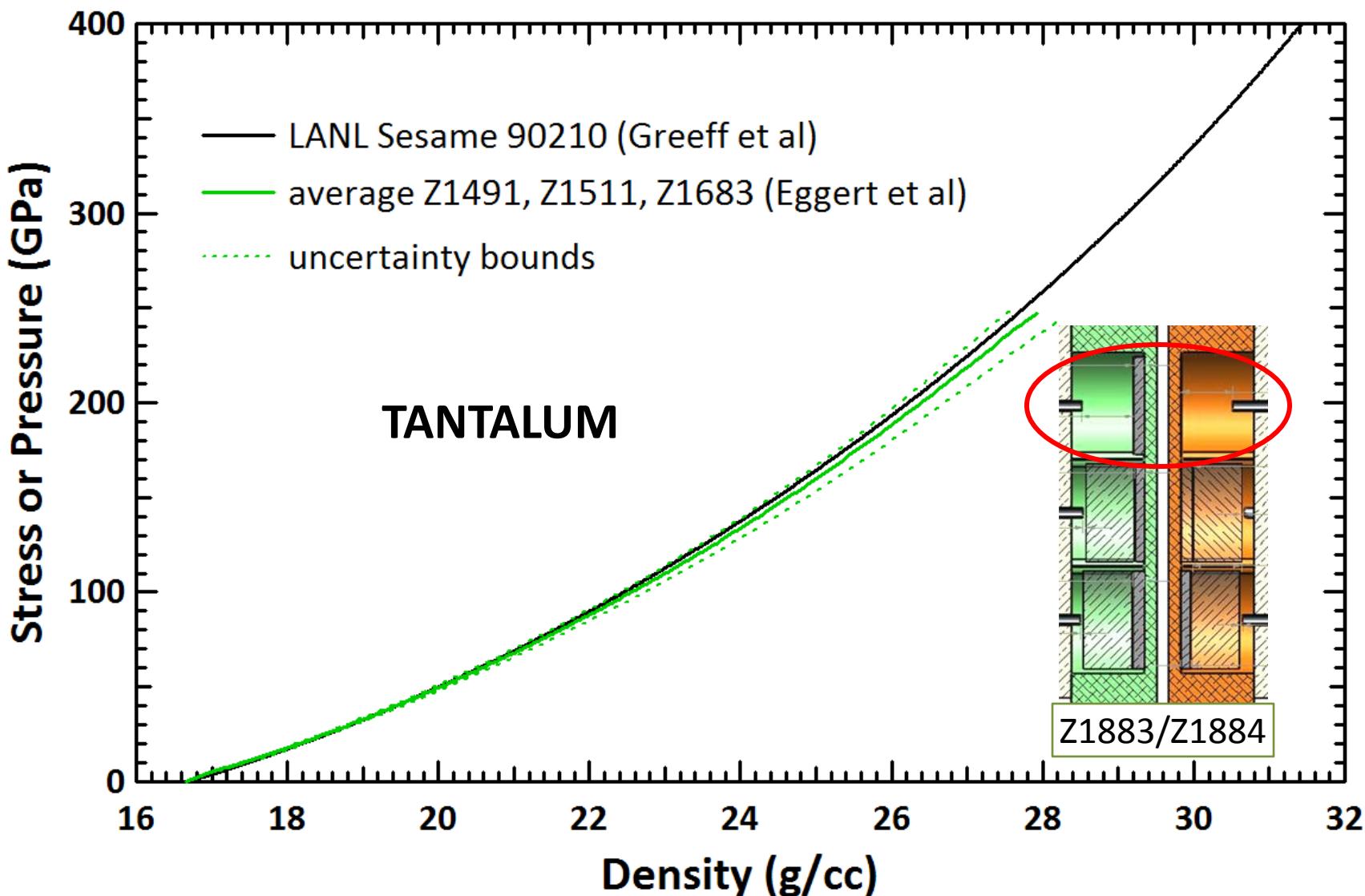
1. measure velocity at back faces of sample and opposite electrode
2. use optimization to determine  $B(t)$  from electrode measurement
3. use  $B(t)$  and first-guess sample EOS (Sesame table + strength) to simulate electrode/sample interface “zero-thickness” velocity
4. perform inverse Lagrangian analysis on simulated “zero-thickness” velocity and measured back-face velocity of sample
5. convert resulting  $\sigma_x(\rho)$  curve to full tabular EOS by assuming constant  $c_V$  and  $\Gamma/V$ , equating stress to pressure (strength folded into EOS)
6. use  $B(t)$  and new tabular EOS to simulate electrode/sample interface
7. repeat steps 4-6 until material response converges



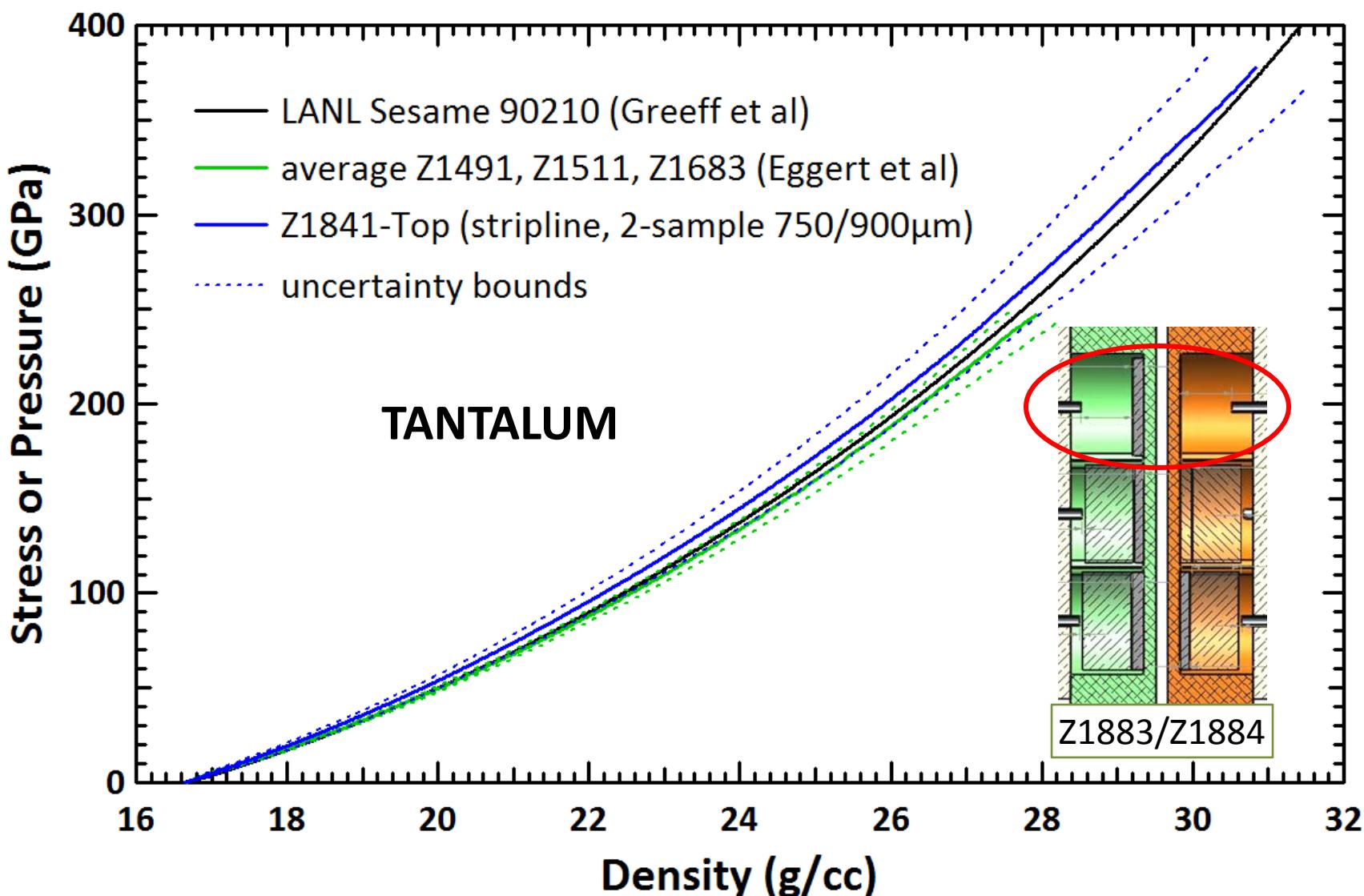
# Outer loop of single-sample approach converges



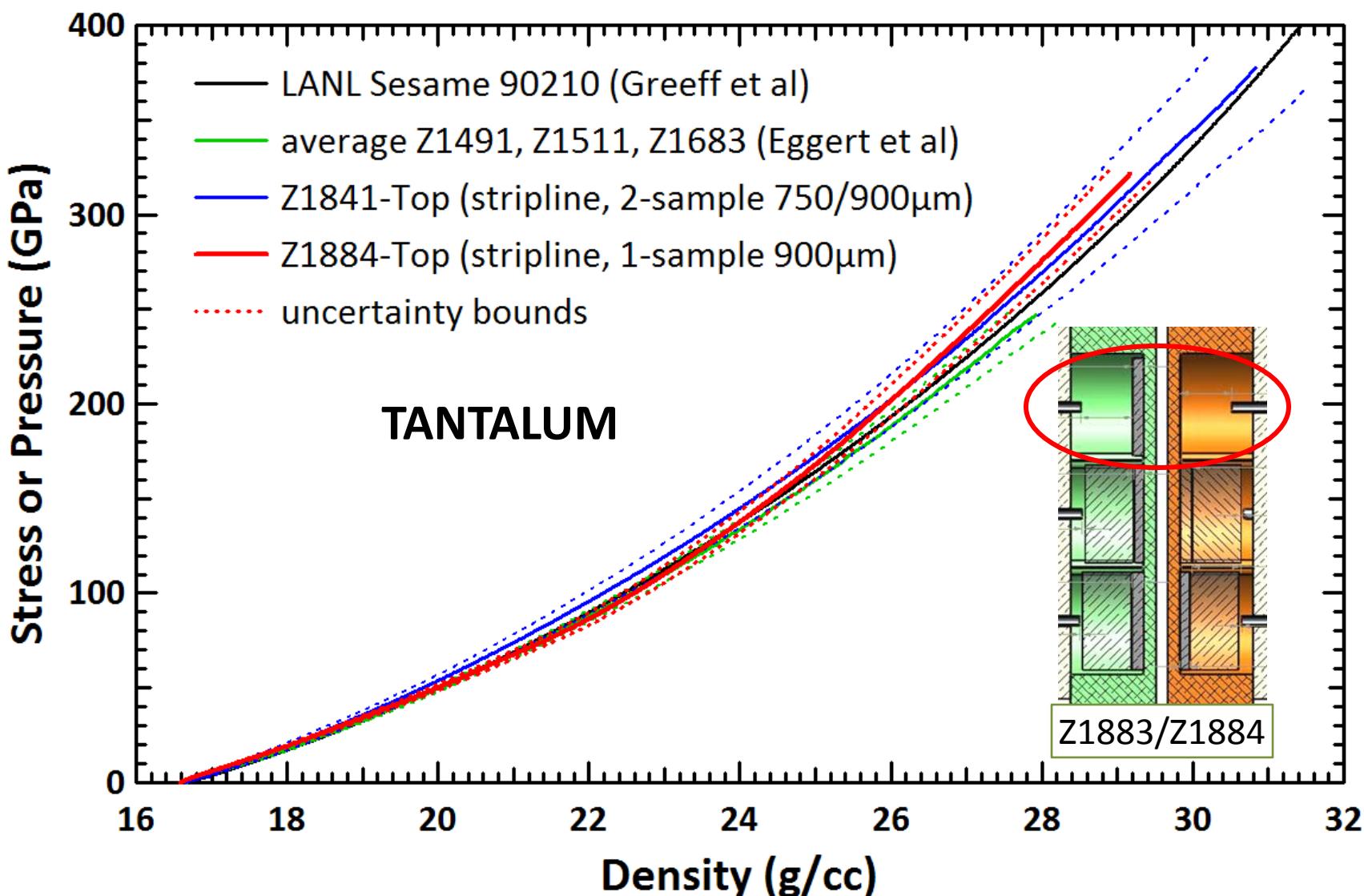
# Single-sample measurement of tantalum to 320 GPa decreases uncertainty over two-sample measurement



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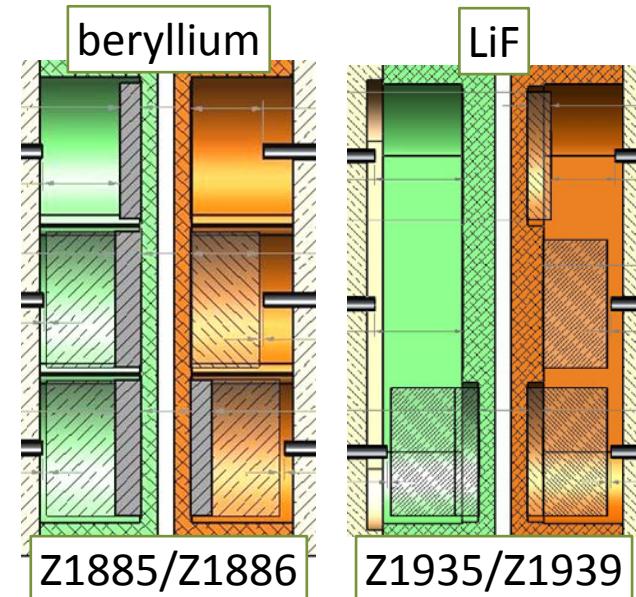


# Single-sample measurement of tantalum to 320 GPa decreases uncertainty over two-sample measurement



# Further work is planned to fully establish a capability for multi-megabar ramp compression measurements

- Analyze additional single-sample and two-sample data sets on Ta, Be, LiF, Al, Cu, and Au
- Use independently measured strength to correct quasi-isentrope to isentrope
- Extract LiF index-of-refraction window correction
- Quantify sensitivity of results to
  1. aluminum EOS used for B-field optimization
  2. LiF EOS used for windowed samples
  3. B-field gradients across sample diameter



- The stripline load with the single-sample analysis approach has the **potential** to measure quasi-isentropic loading paths to multi-megabar pressures with uncertainties of ~1% in density and ~3% in stress
- Recent design and pulse-shaping improvements suggest measurements to > 5 Mbar are possible on high-Z materials at full machine charge voltage